

**Qualitative Analysis Blunders:
the Perils of Automatic Peak Identification
in EDS Analysis**

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Automatic Qualitative Analysis (Peak ID)

- **The critical first step in any EDS analysis: correctly identifying the elements responsible for the peaks**
- Can we trust automatic qualitative analysis (peak identification) to always identify peaks of major constituents correctly?
 - **Major: Concentration, $C > 0.1$ mass fraction (>10 weight %)**
 - **Minor: $0.01 \leq C \leq 0.1$ (1 to 10 weight %)**
 - **Trace: $C < 0.01$ (< 1 weight %)**

Automatic Qualitative Analysis (Peak ID)

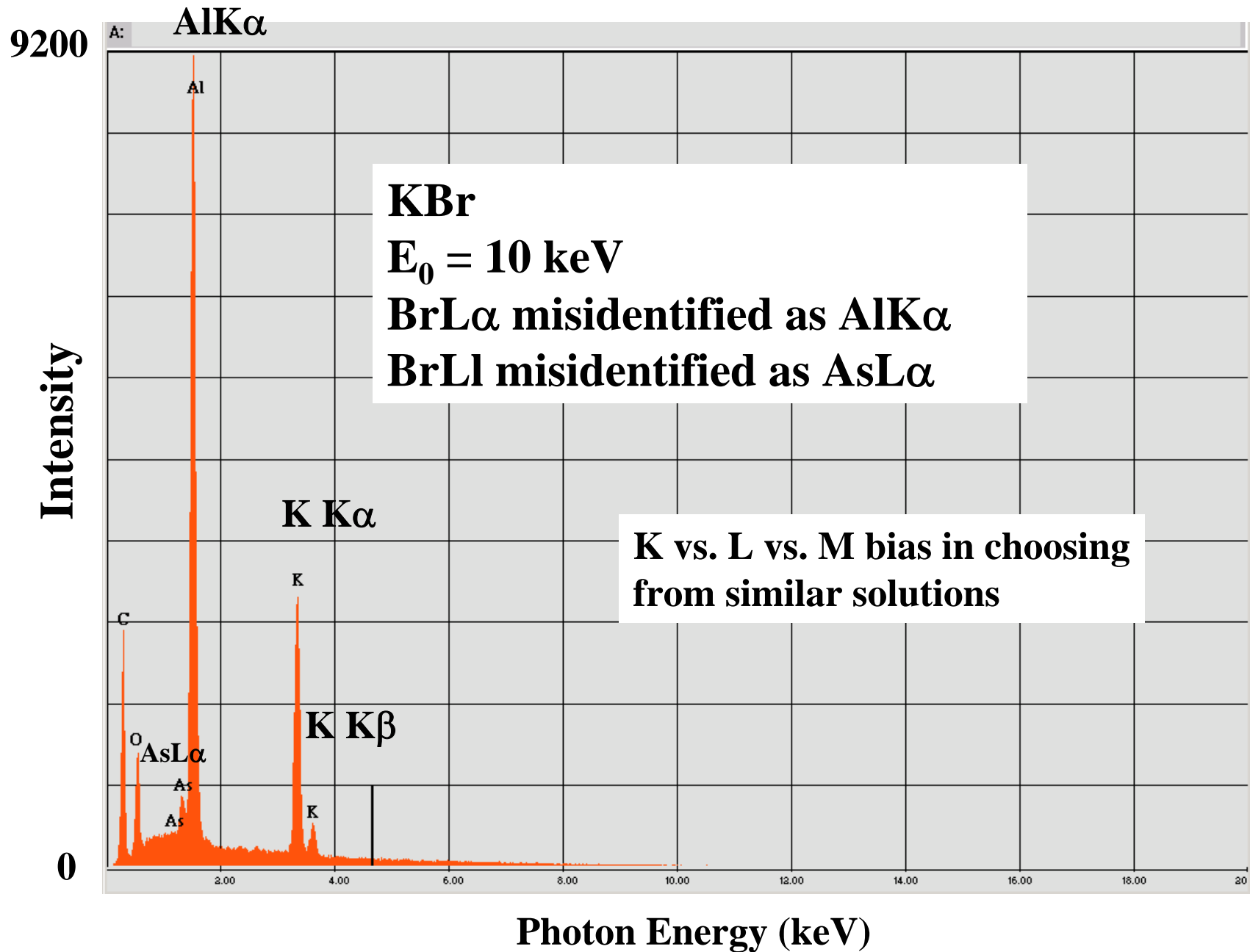
- Test automatic peak ID of commercial systems for the easiest case:
major constituents
 - **big peaks (high peak-to-background)**
 - **high counting statistics**
 - **no interferences**
 - **simple spectra**
- **Results on Peak ID of major constituents presented at M&M 2004, 2005, and 2006 conferences. Papers published:**
- 1. Dale E. Newbury, “Misidentification of Major Constituents by Automatic Qualitative Energy Dispersive X-ray Microanalysis: A Problem that Threatens the Credibility of the Analytical Community”, *Microscopy and Microanalysis* (2005) 11, 545-561.
- 2. Dale E. Newbury, “Mistakes Encountered during Automatic Peak Identification in Low Beam Energy X-ray Microanalysis,” *SCANNING*, v 29 (2007) 137-151.

Testing Automatic Peak Identification

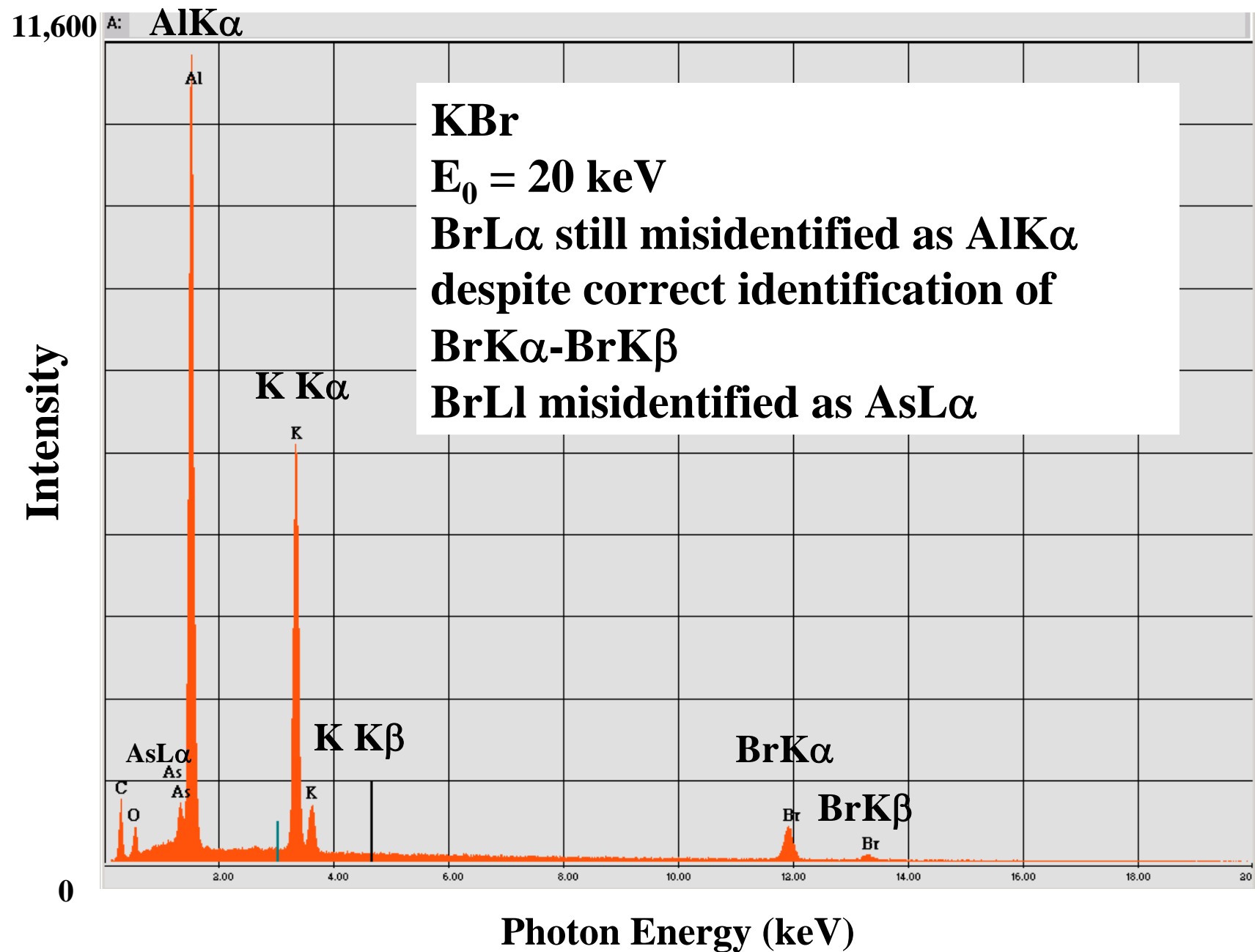
Protocol

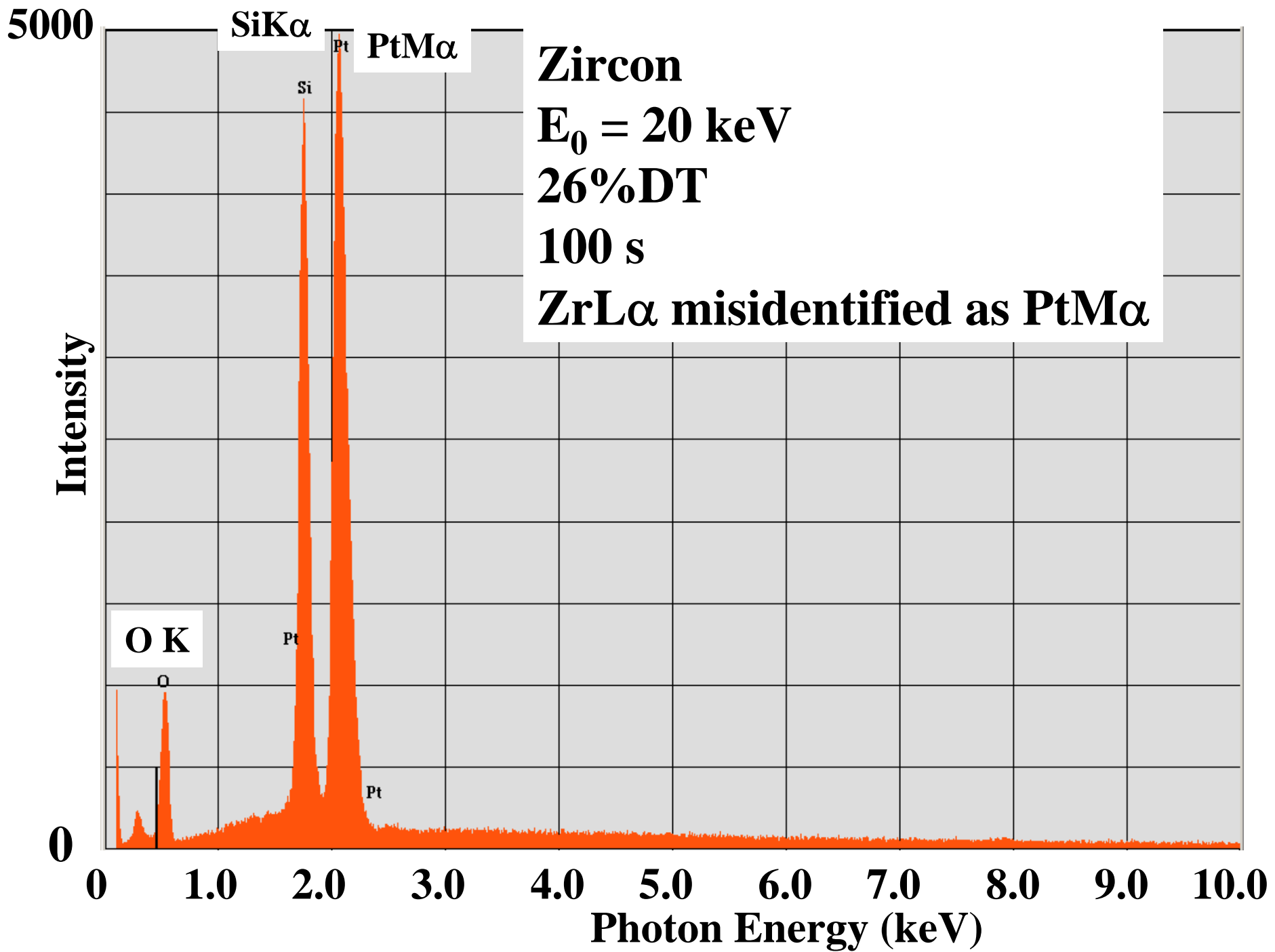
1. Select the pulse processing time constant to operate at optimum resolution for the particular EDS system.
2. Calibrate the EDS system (e.g., CuL and CuK α , preferably AlK and CuK α) and check the peak channel locations of some intermediate peaks, e.g., SiK, CaK α , TiK α , FeK α
3. Select a beam current to keep deadtime below 20%.
4. Obtain at least 1,000 counts in the peak channel for the peaks of interest.

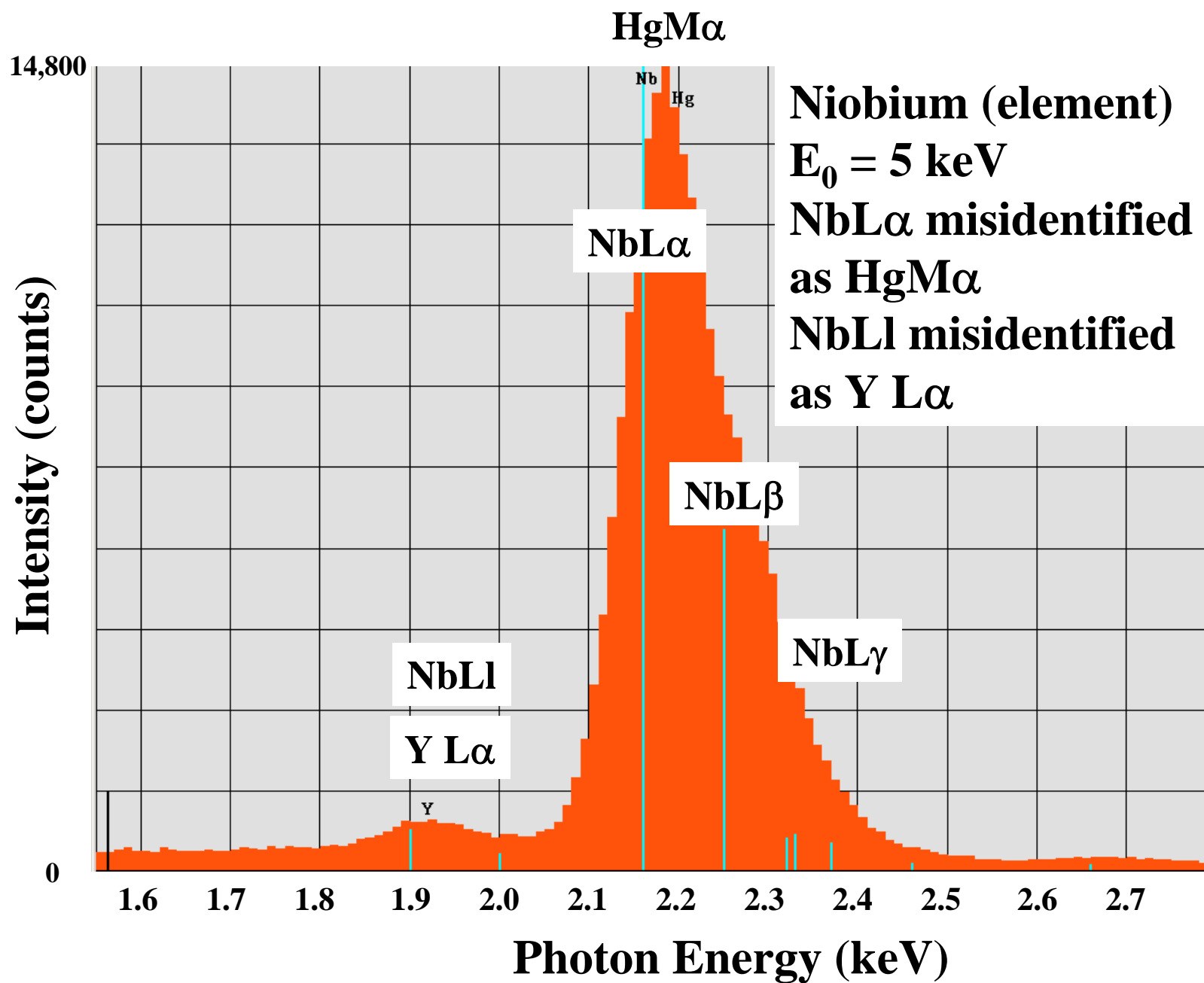
EDS Manufacturer # 1



EDS Manufacturer # 1

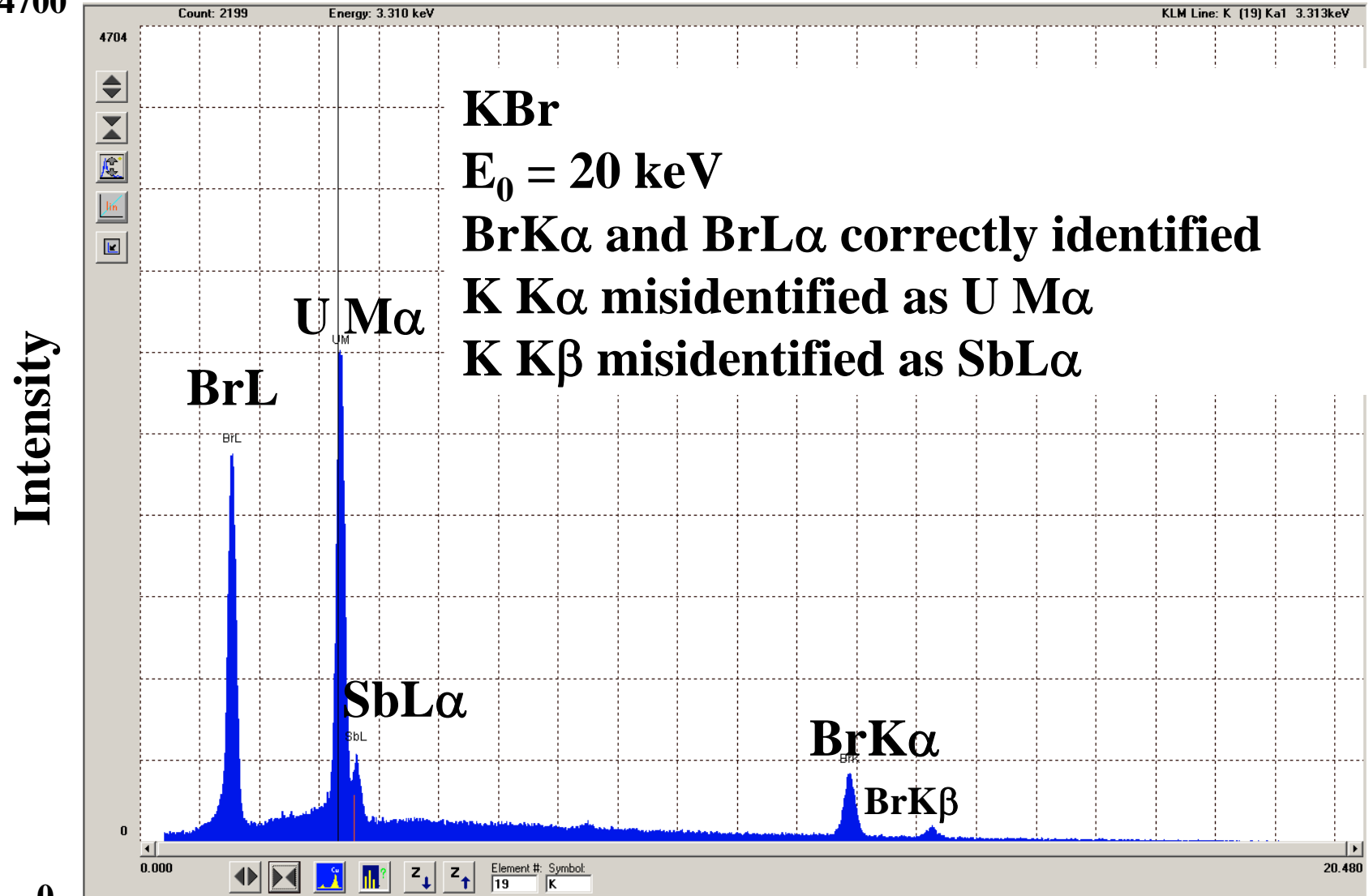






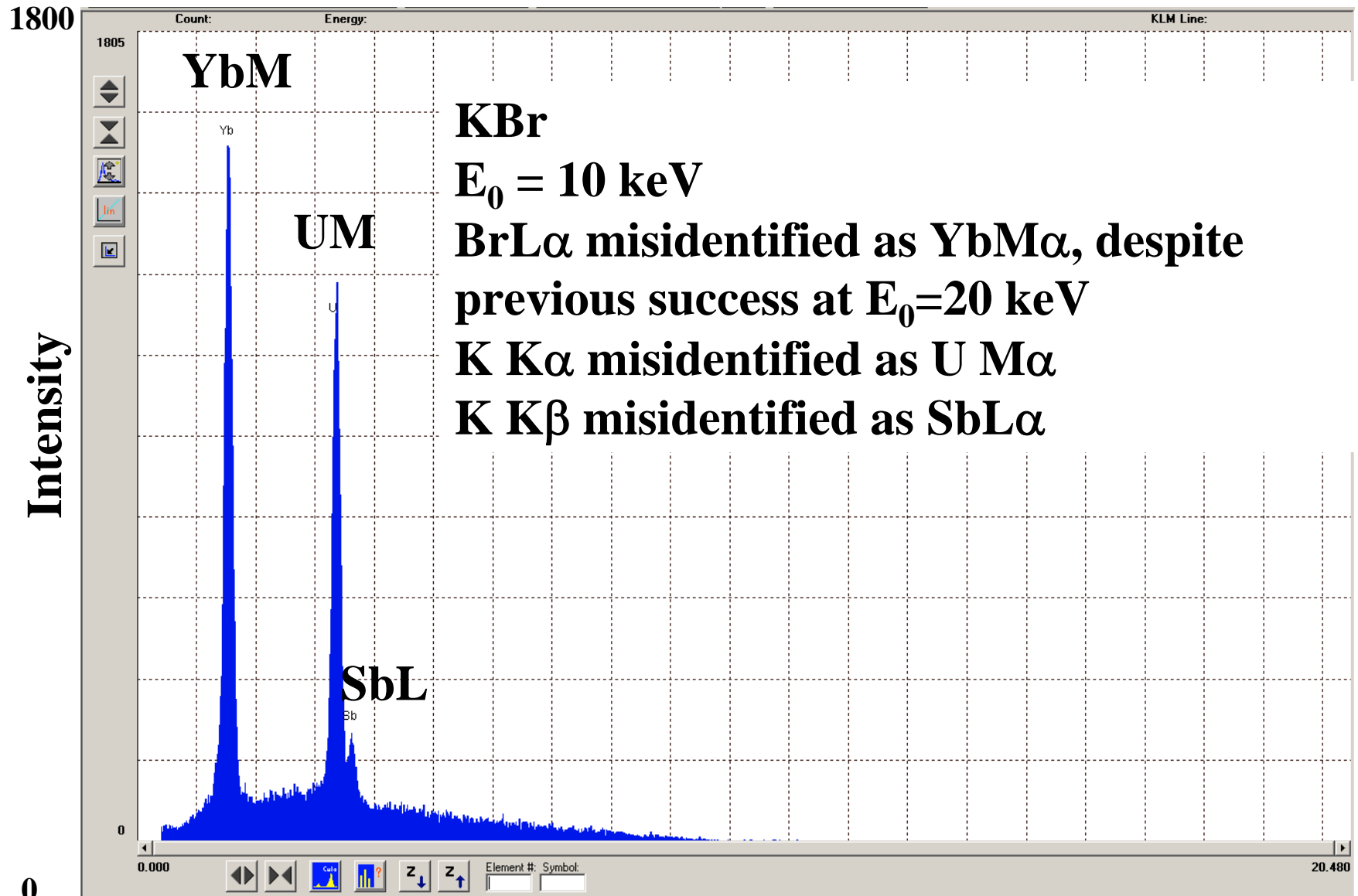
EDS Manufacturer # 2

4700



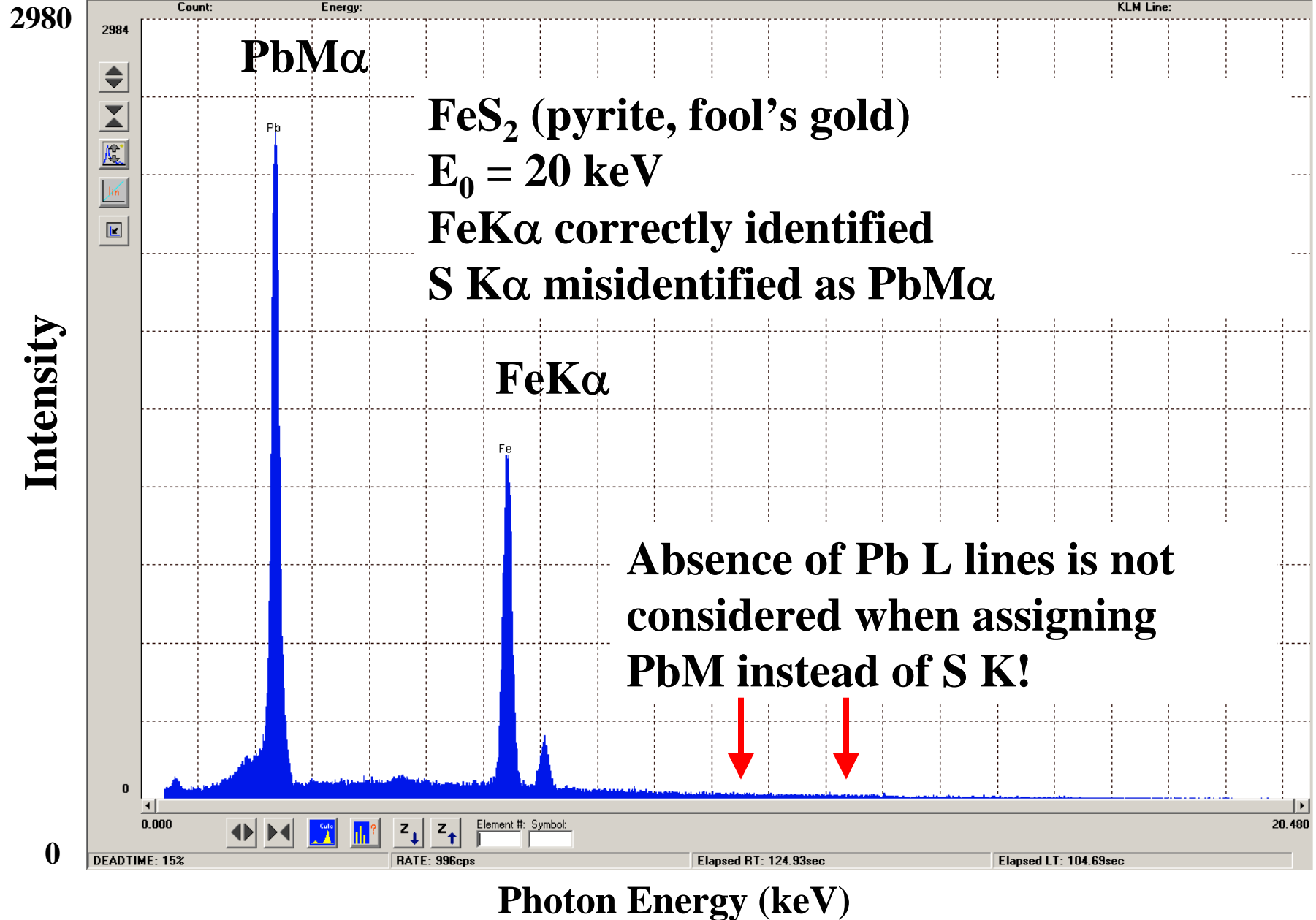
Photon Energy (keV)

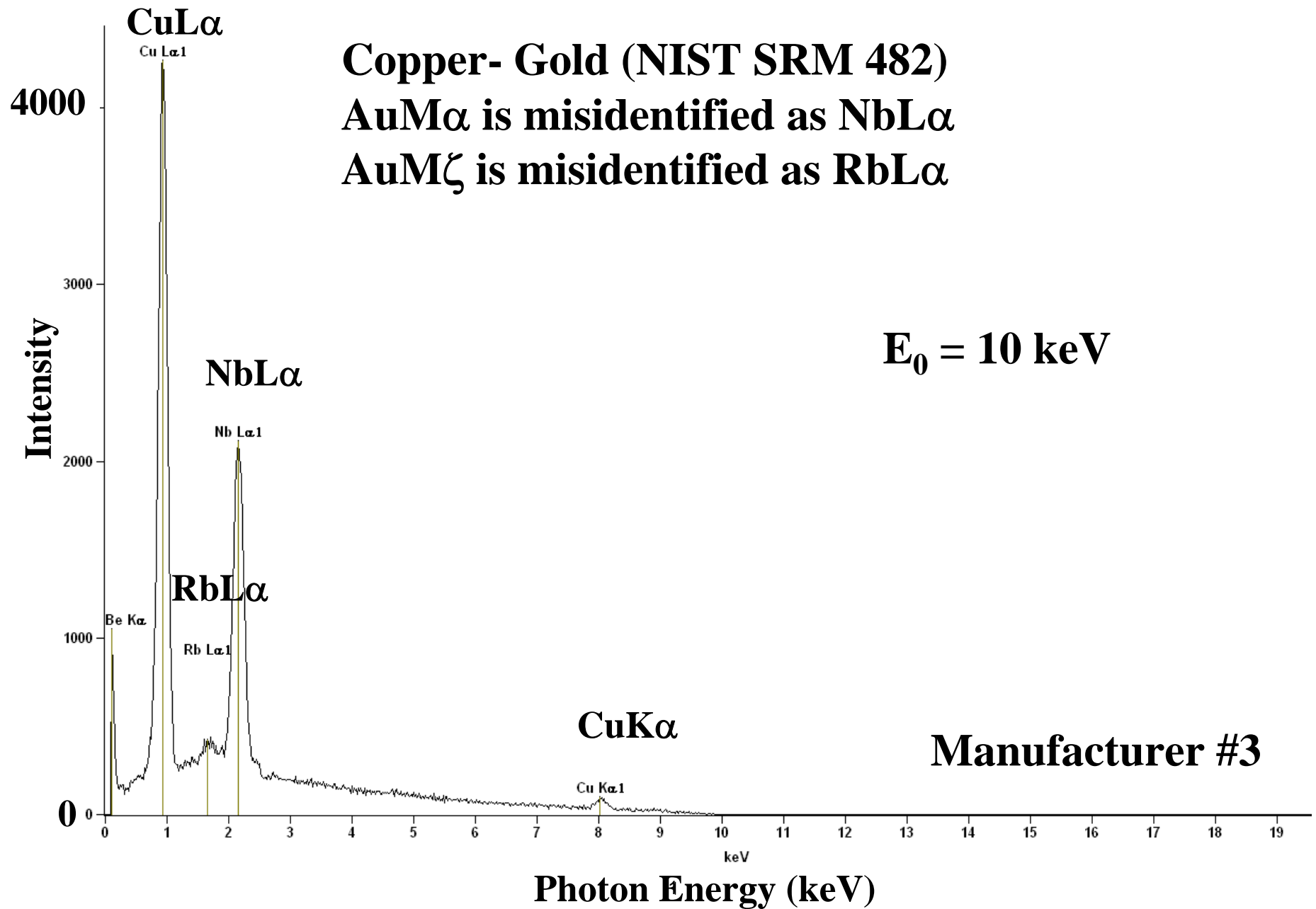
EDS Manufacturer # 2



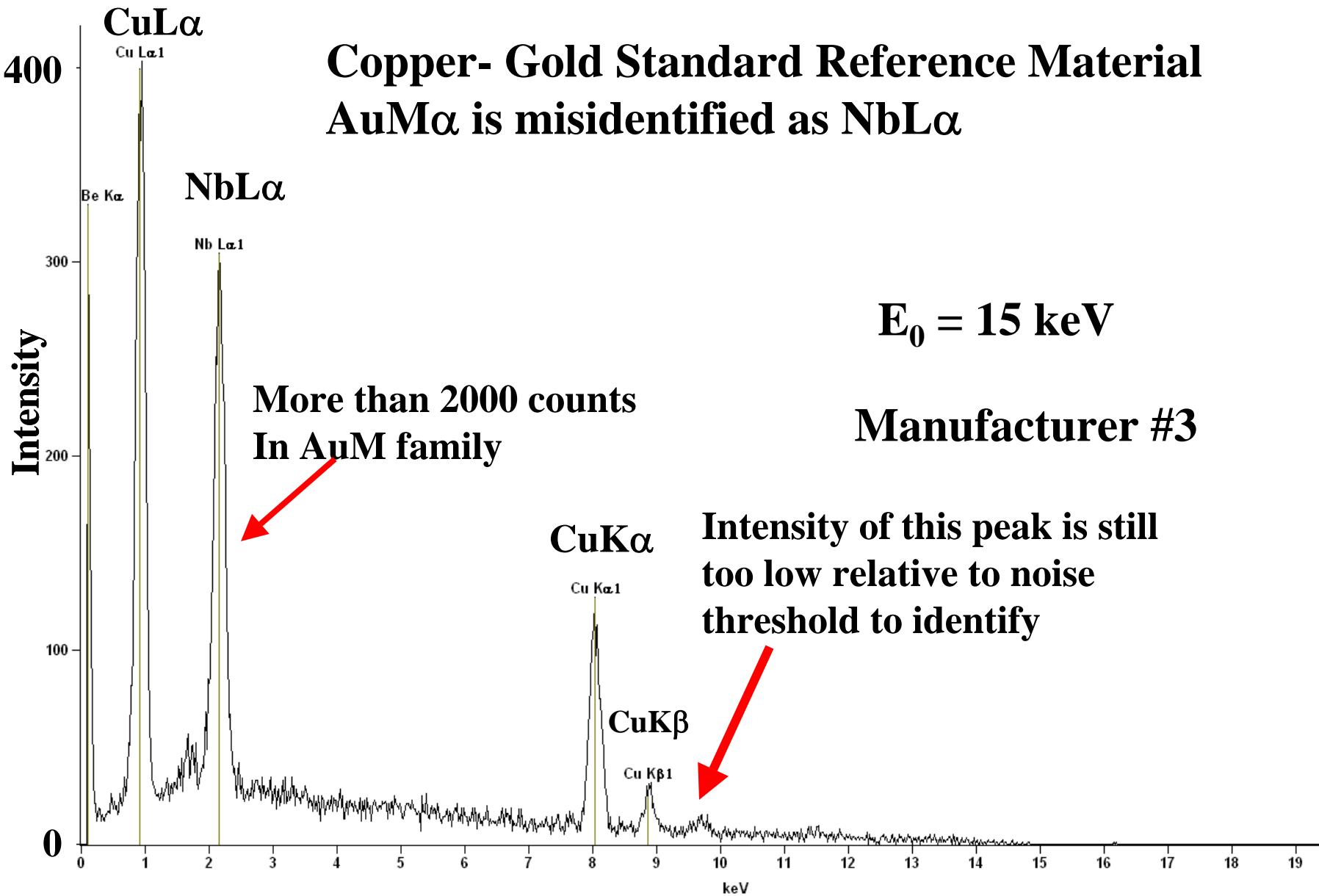
Photon Energy (keV)

EDS Manufacturer # 2





Copper- Gold Standard Reference Material AuM α is misidentified as NbL α



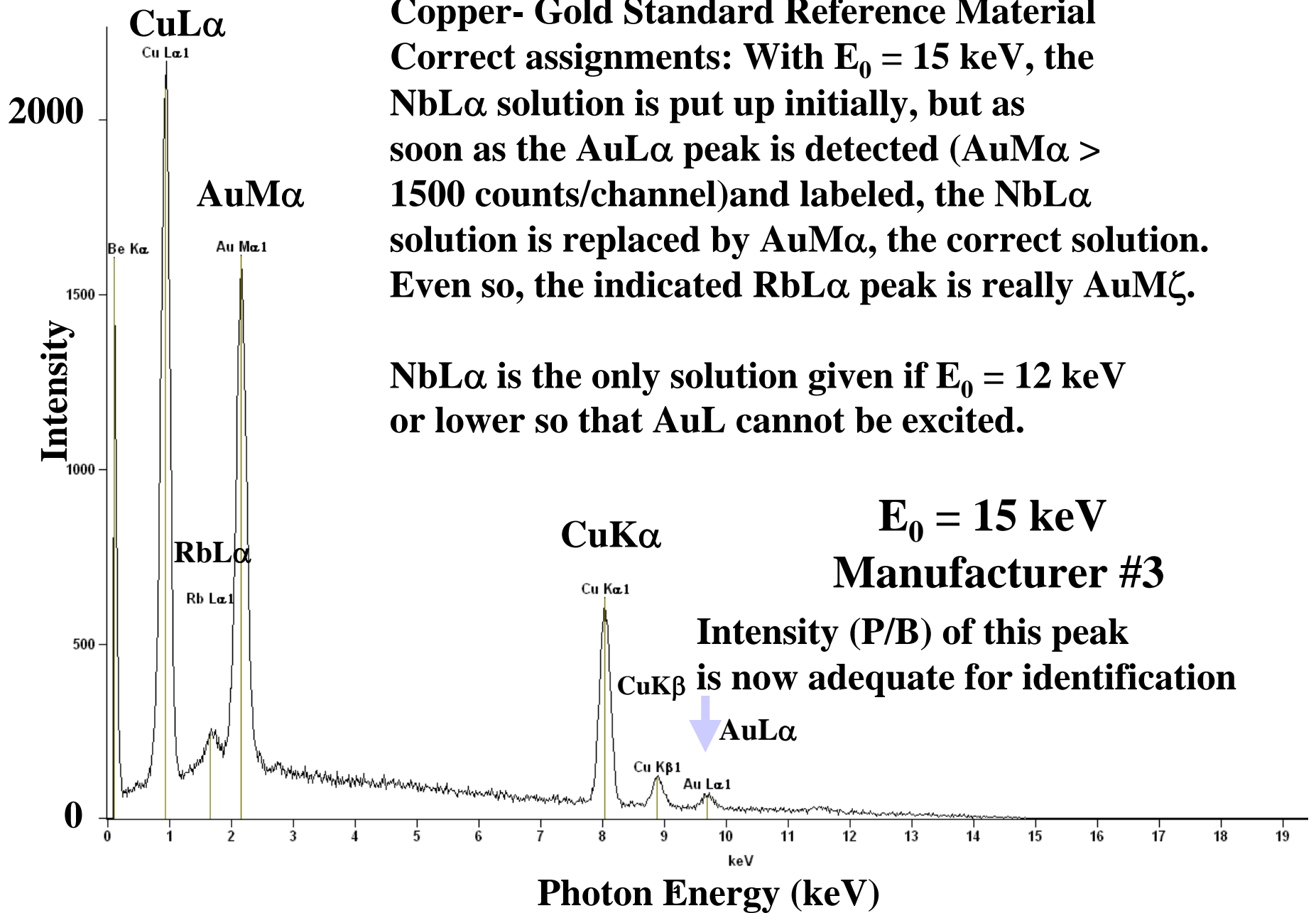
$E_0 = 15 \text{ keV}$

Manufacturer #3

More than 2000 counts
In AuM family

Intensity of this peak is still
too low relative to noise
threshold to identify

Photon Energy (keV)



Possible Troublemakers

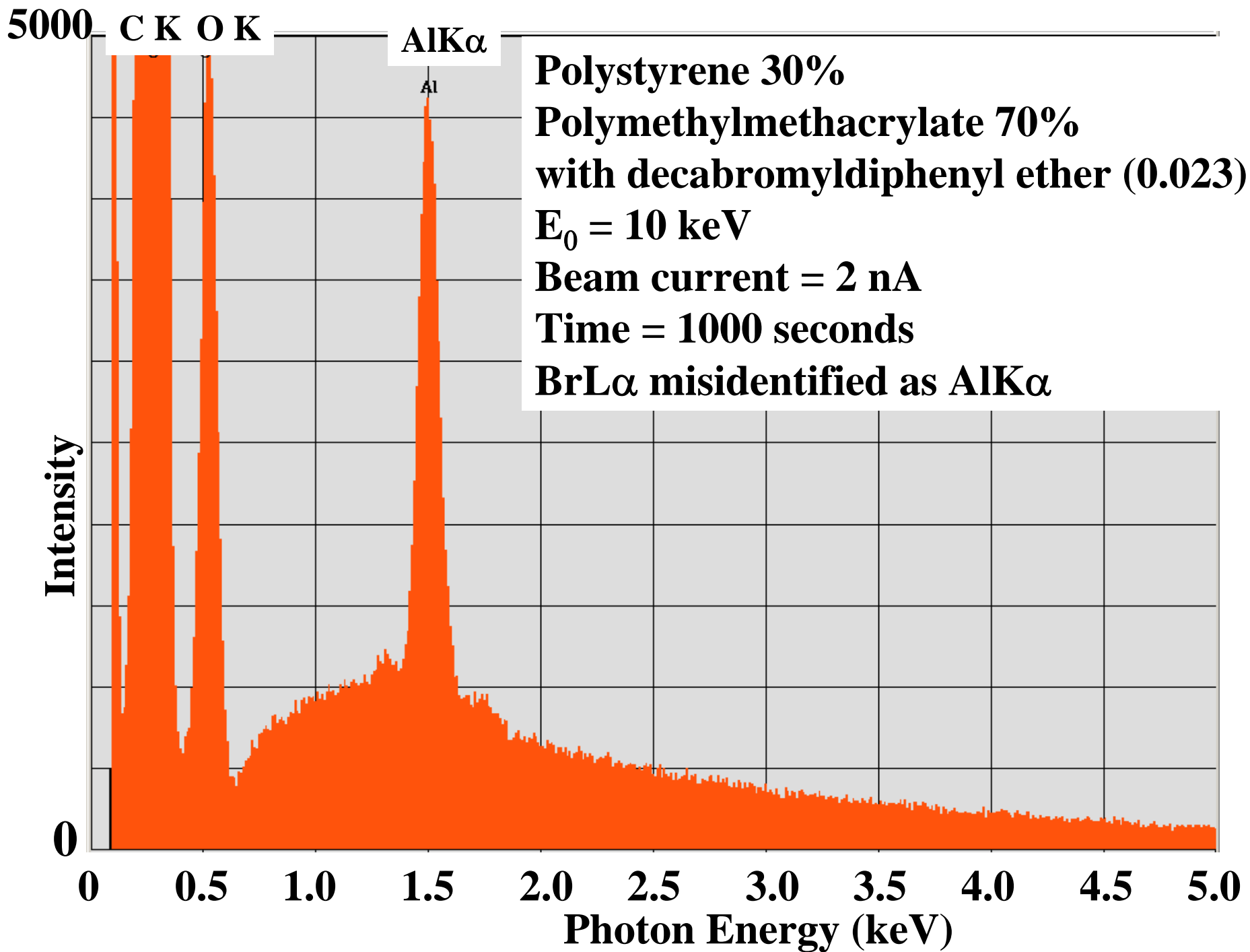
(Closely spaced K-L-M peaks; not necessarily a complete list!)

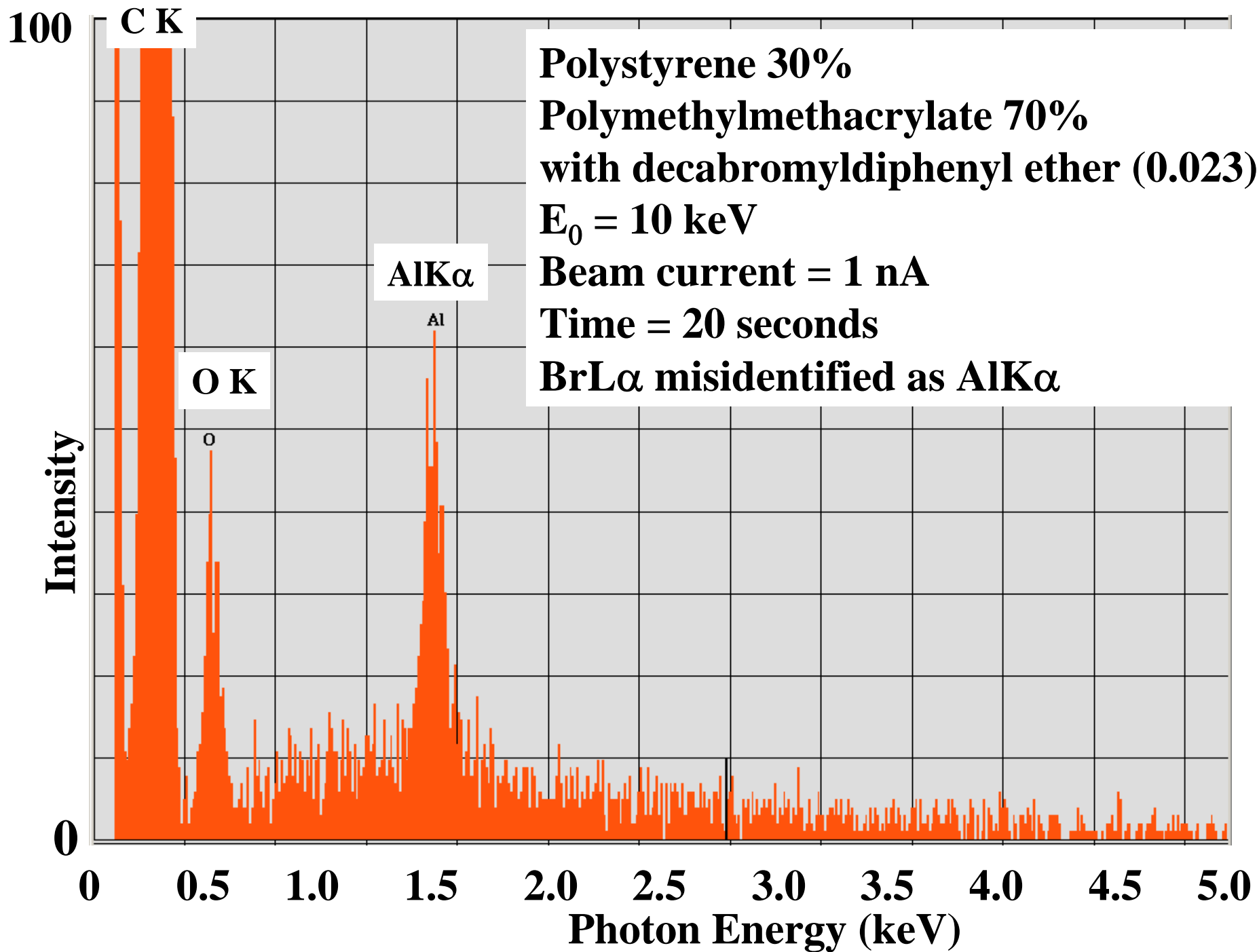
- 0.390-0.395 keV N K (0.392); ScL α (0.395)
- 0.510-0.525 keV O K (0.523); V L α (0.511)
- 0.670-0.710 keV **F K (0.677); FeL α (0.705)**
- 0.845-0.855 keV NeK α (0.848); NiL α (0.851)
- 1.00-1.05 keV **NaK α (1.041); ZnL α (1.012); PmM α (1.032)**
- 1.20-1.30 keV MgK α (1.253); AsL α (1.282); TbM α (1.246)
- 1.45-1.55 keV **AlK α (1.487); BrL α (1.480); YbM α (1.521)**
- 1.70-1.80 keV **SiK α (1.740); TaM α (1.709); W M α (1.774)**
- 2.00-2.05 keV PK α (2.013); **ZrL α (2.042); PtM α (2.048)**
- 2.10-2.20 keV **NbL α (2.166); AuM α (2.120); HgM α (2.191)**
- 2.28-2.35 keV **S K α (2.307); MoL α (2.293); PbM α (2.342)**
- 2.40-2.45 keV **TcL α (2.424); BiM α (2.419)**
- 2.60-2.70 keV ClK α (2.621); RhL α (2.696)
- 2.95-3.00 keV ArK α (2.956); **AgL α (2.983); ThM α_1 (2.996)**
- 3.10-3.20 keV **CdL α (3.132); U M α_1 (3.170)**
- 3.25-3.35 keV **K K α (3.312); InL α (3.285); U M β (3.336)**
- 4.45-4.55 keV TiK α (4.510); BaL α (4.467)
- 4.90-5.00 keV **TiK β (4.931); V K α (4.949)**

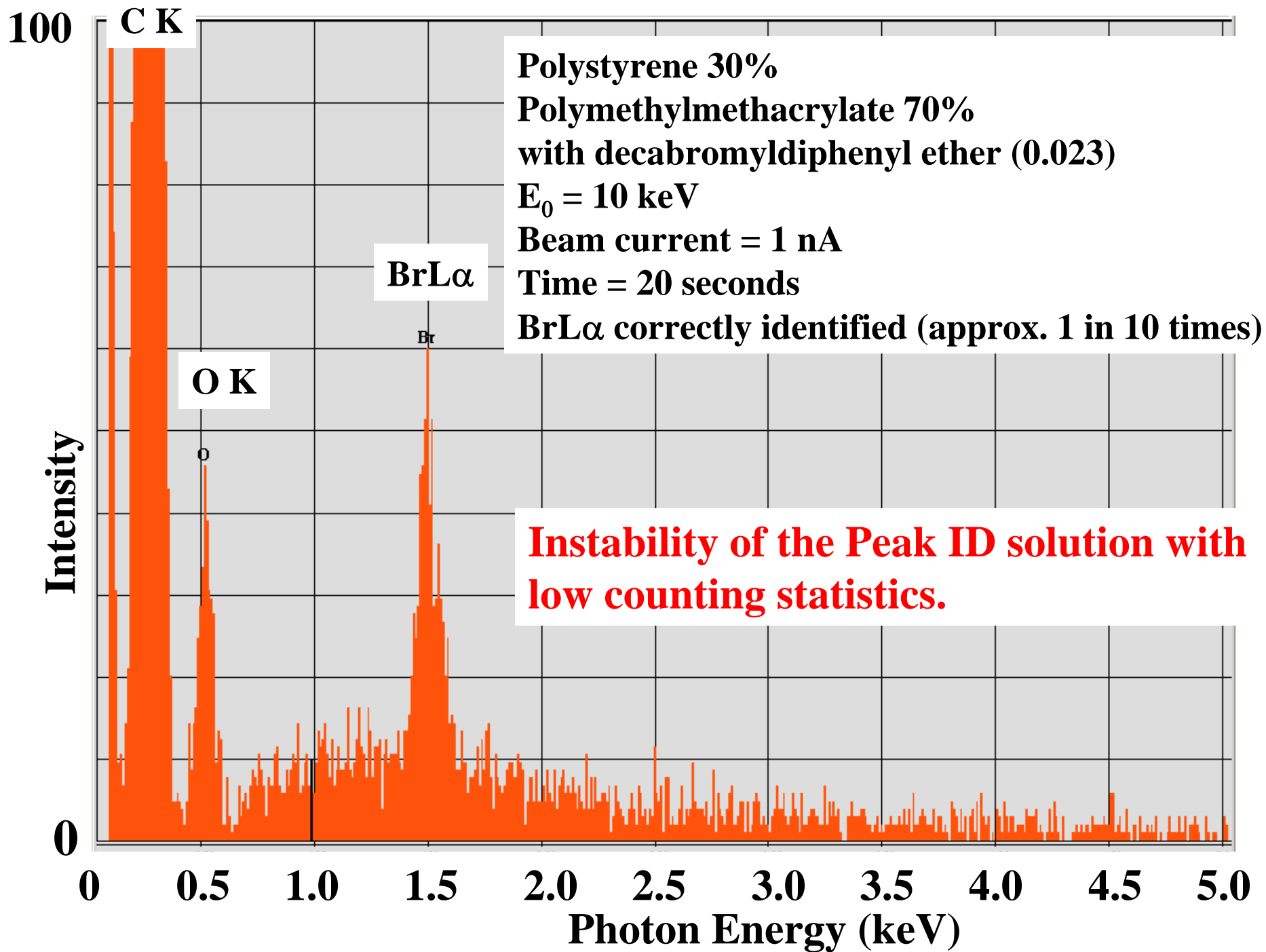
Directly observed

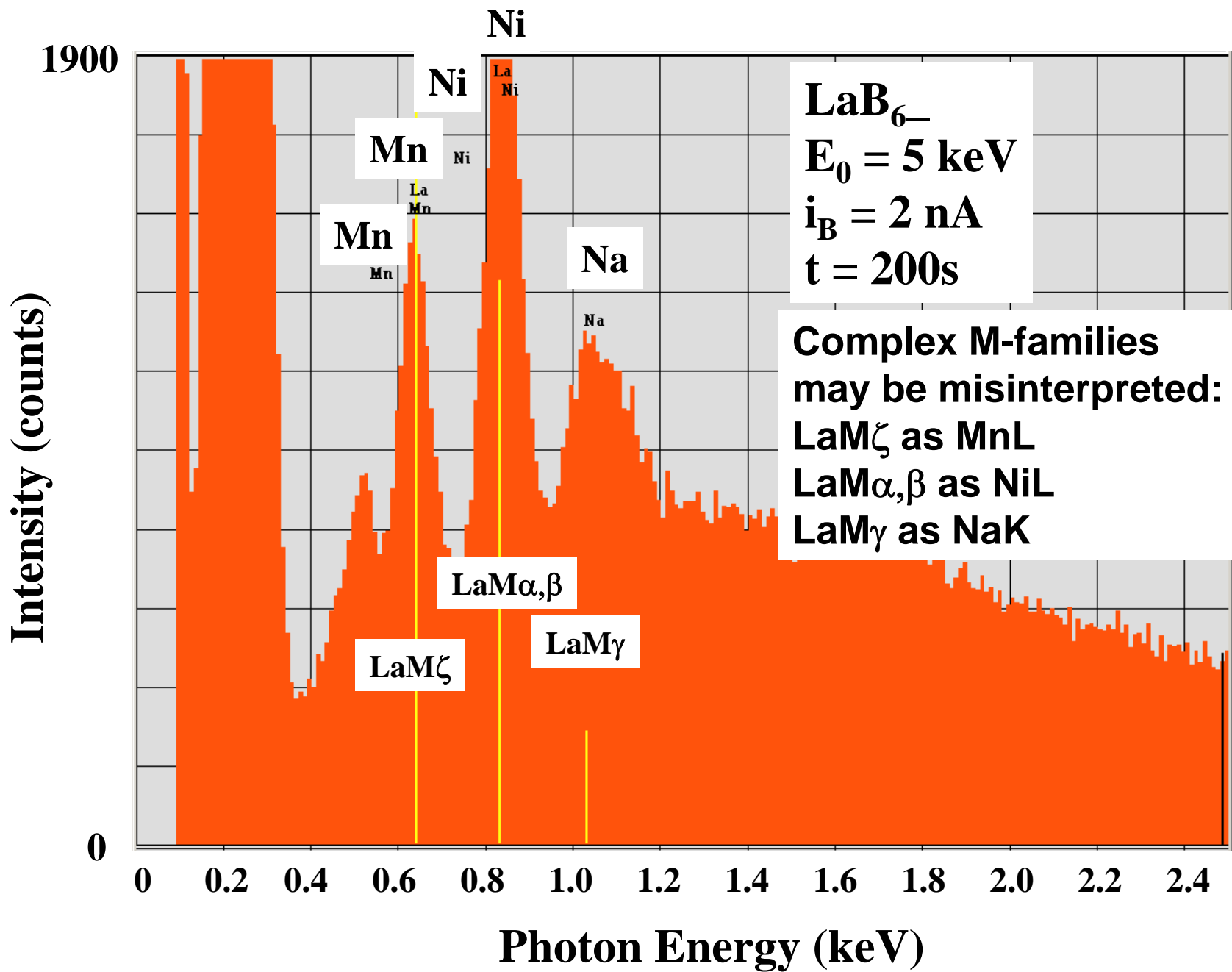
Peak ID for Minor ($0.01 \leq C \leq 0.1$ mass fraction) and Trace ($C < 0.01$ mass fraction) Constituents

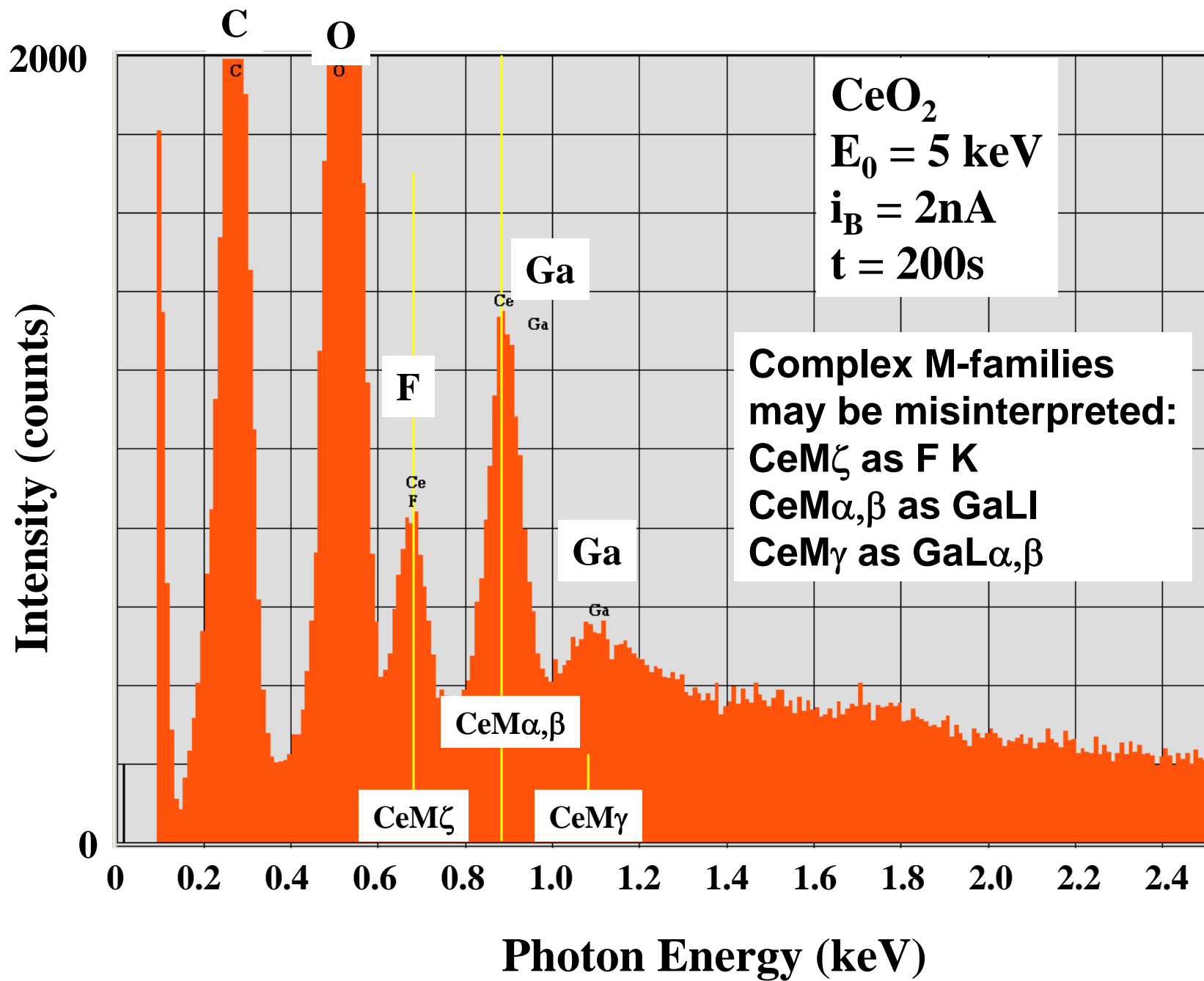
- Things only get worse because of lower peak-to-background
- Round up the usual suspects (Table)
- Additional problems are found that lead to false positives
 - Not recognizing minor family members, L1, M_2N_4
 - Ignoring M-family solution (despite having data!)
 - Escape and sum peaks misinterpreted



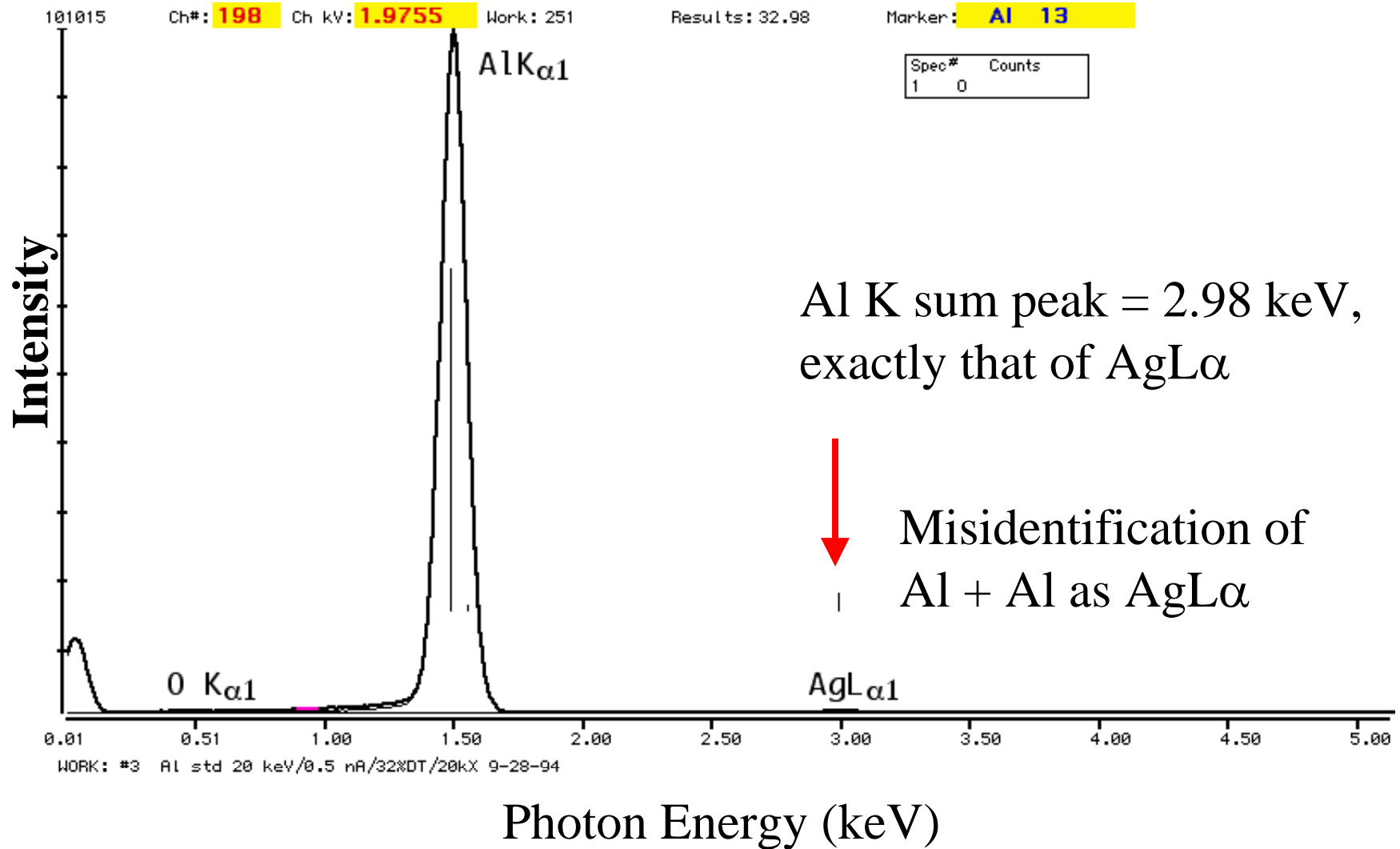




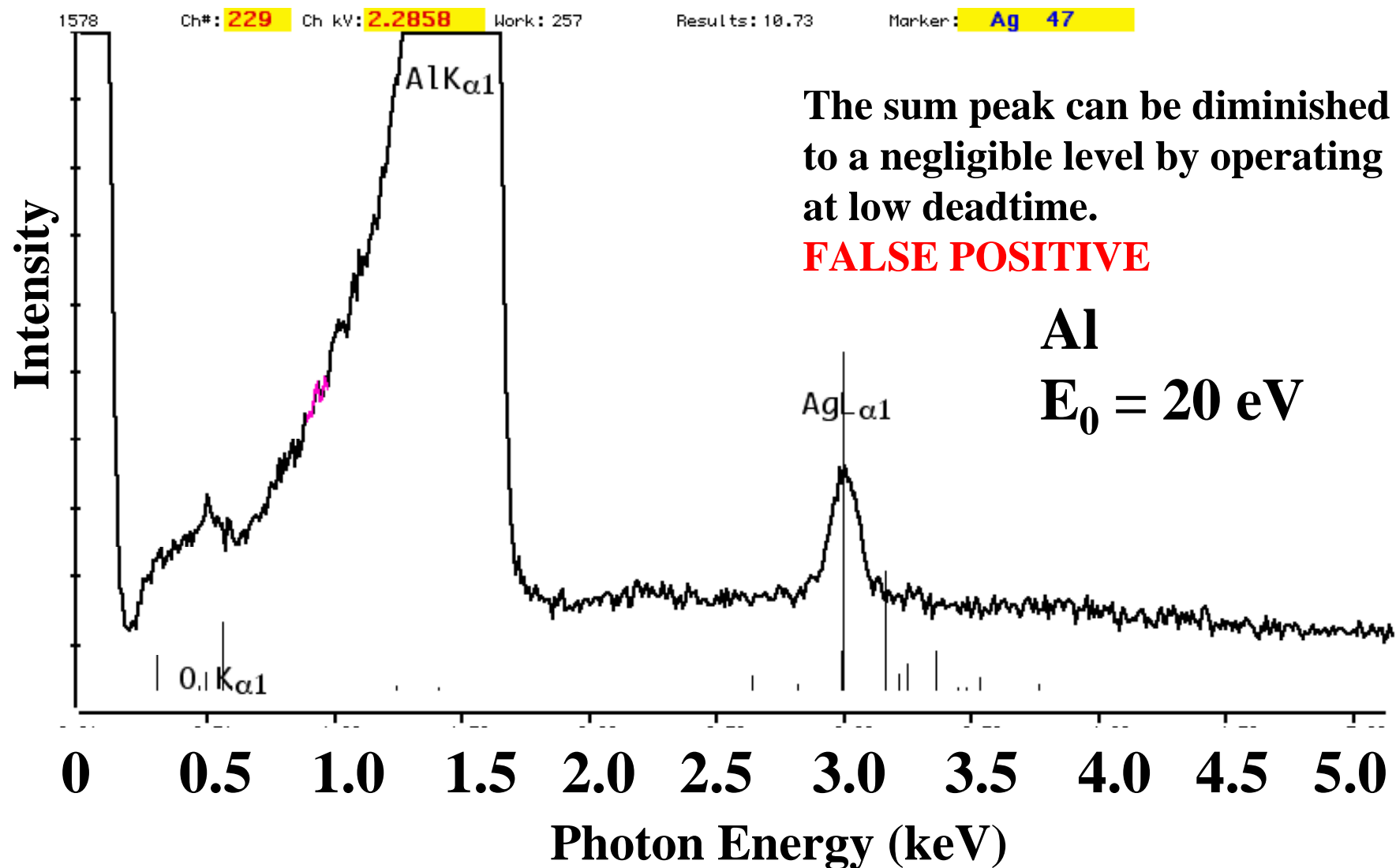


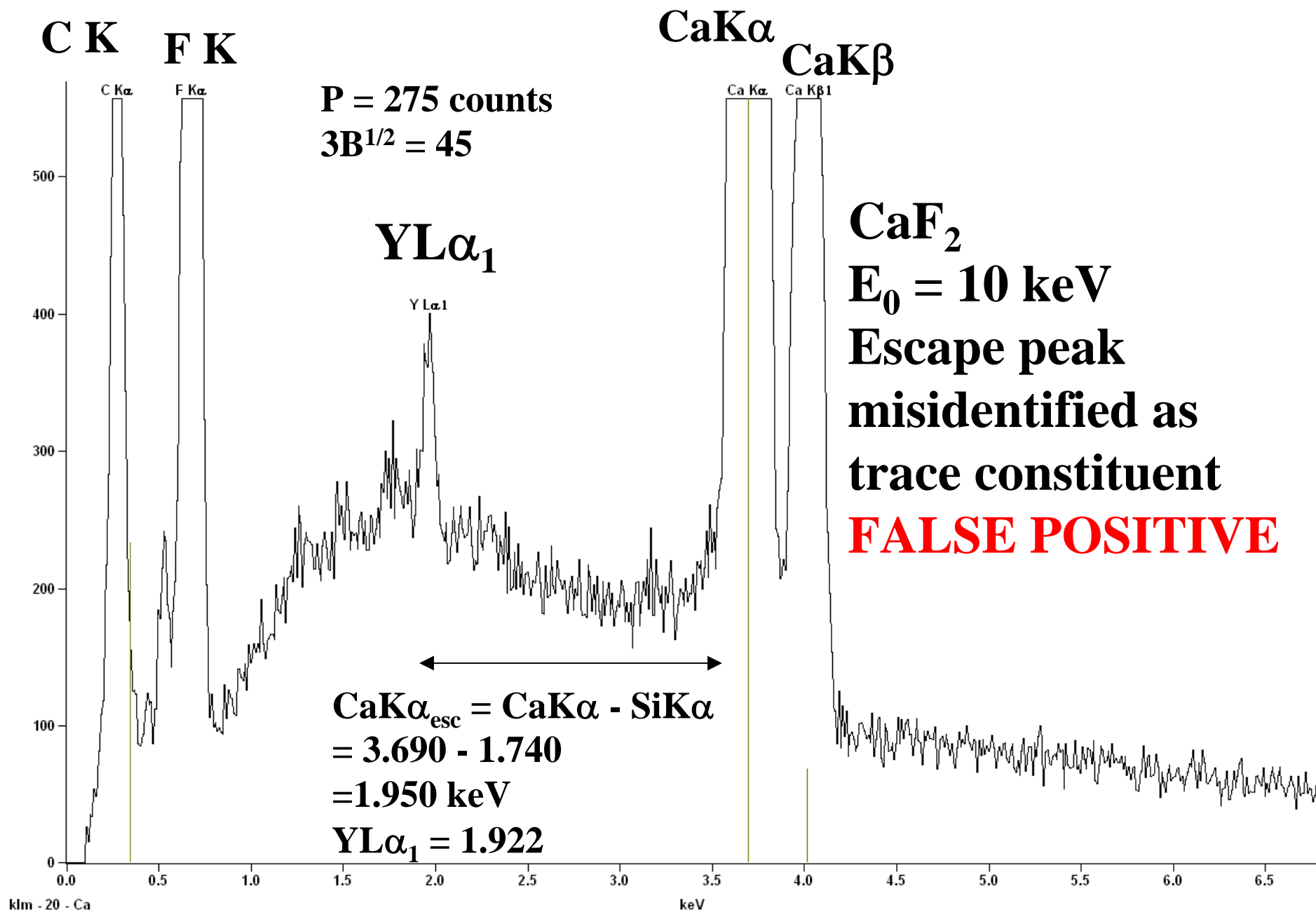


Incorrect identification of sum peak by automatic qualitative analysis



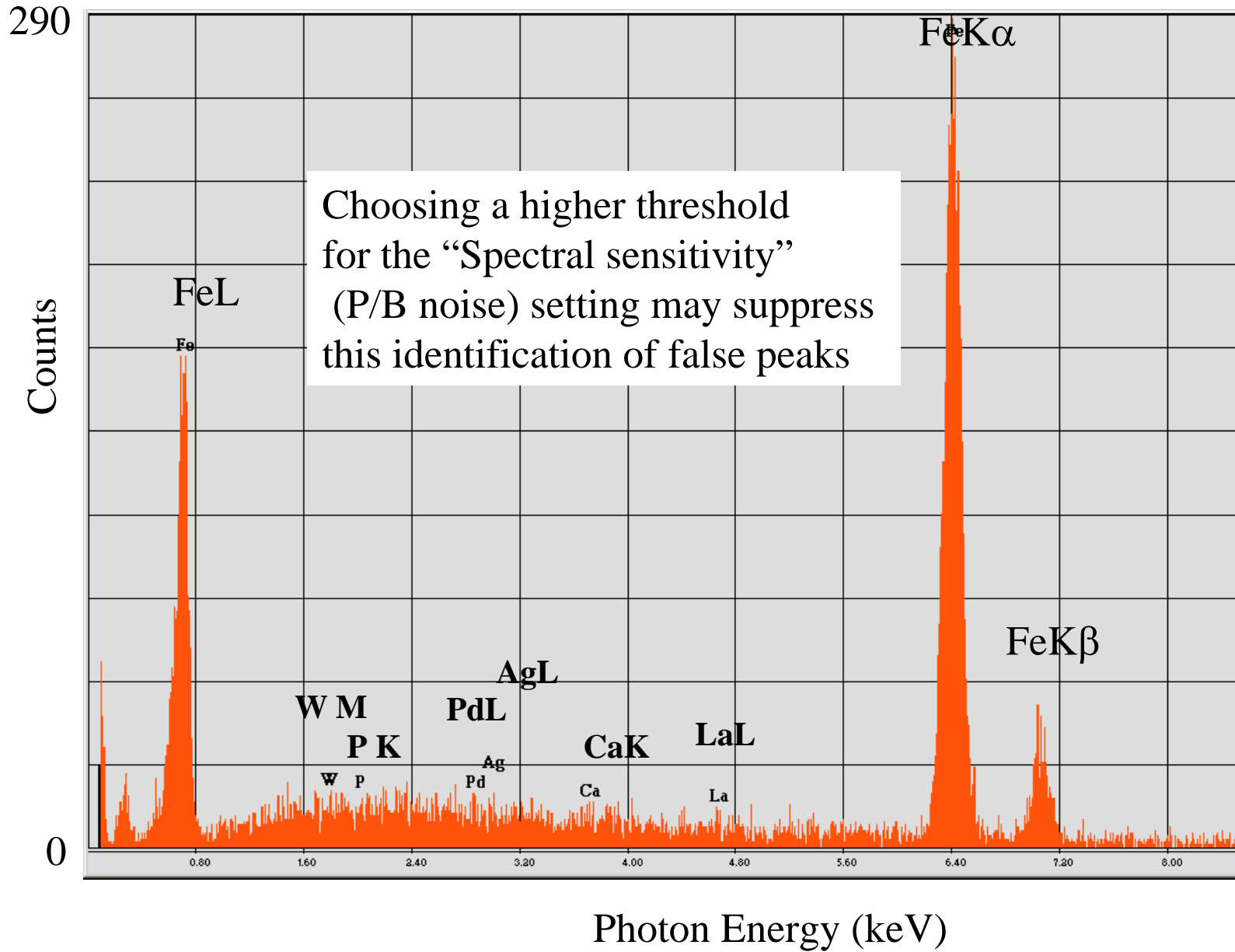
Incorrect identification of sum peak by automatic qualitative analysis



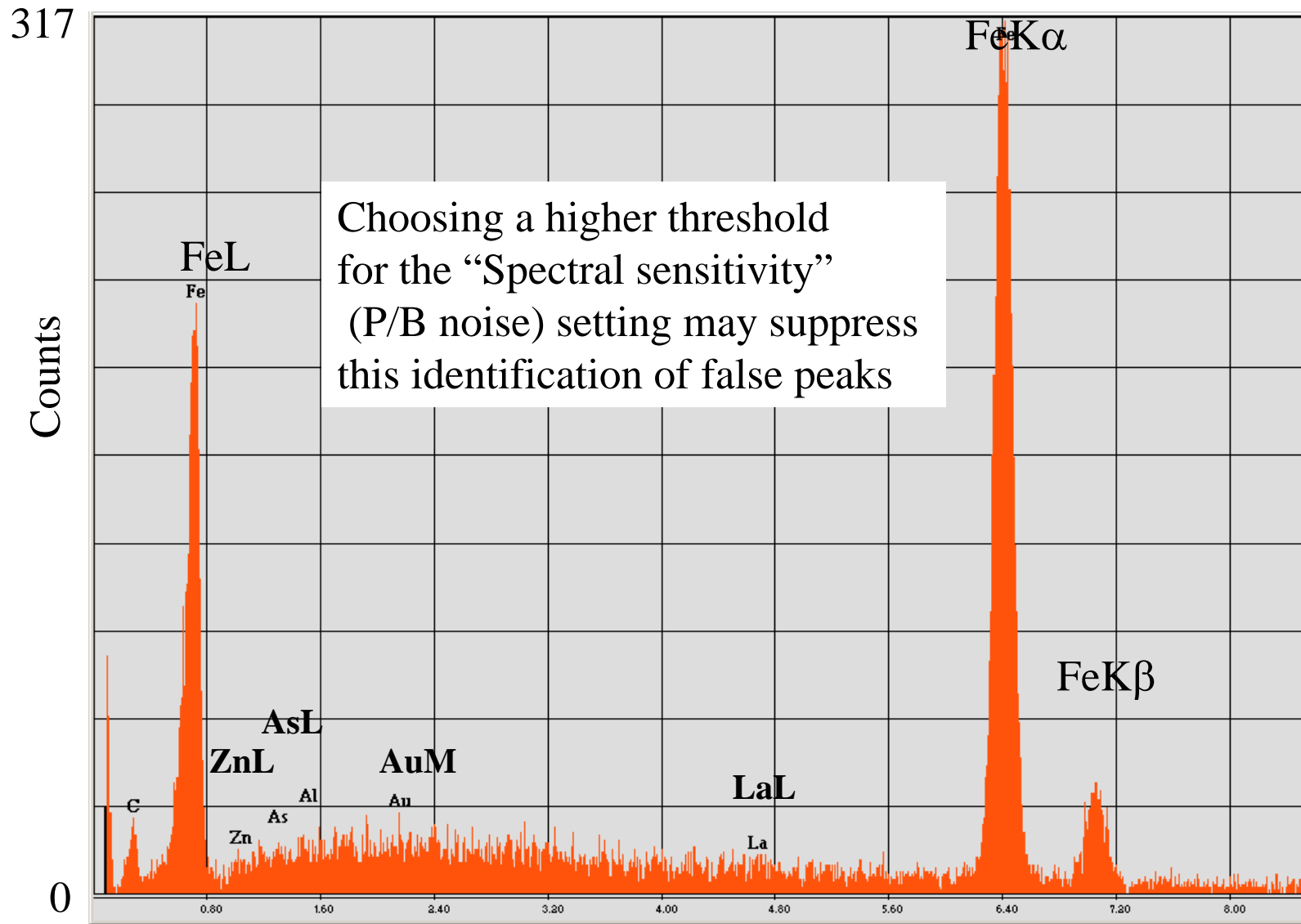


Photon Energy (keV)

Sensitivity to False Peaks: Unstable Solution Changes with Time



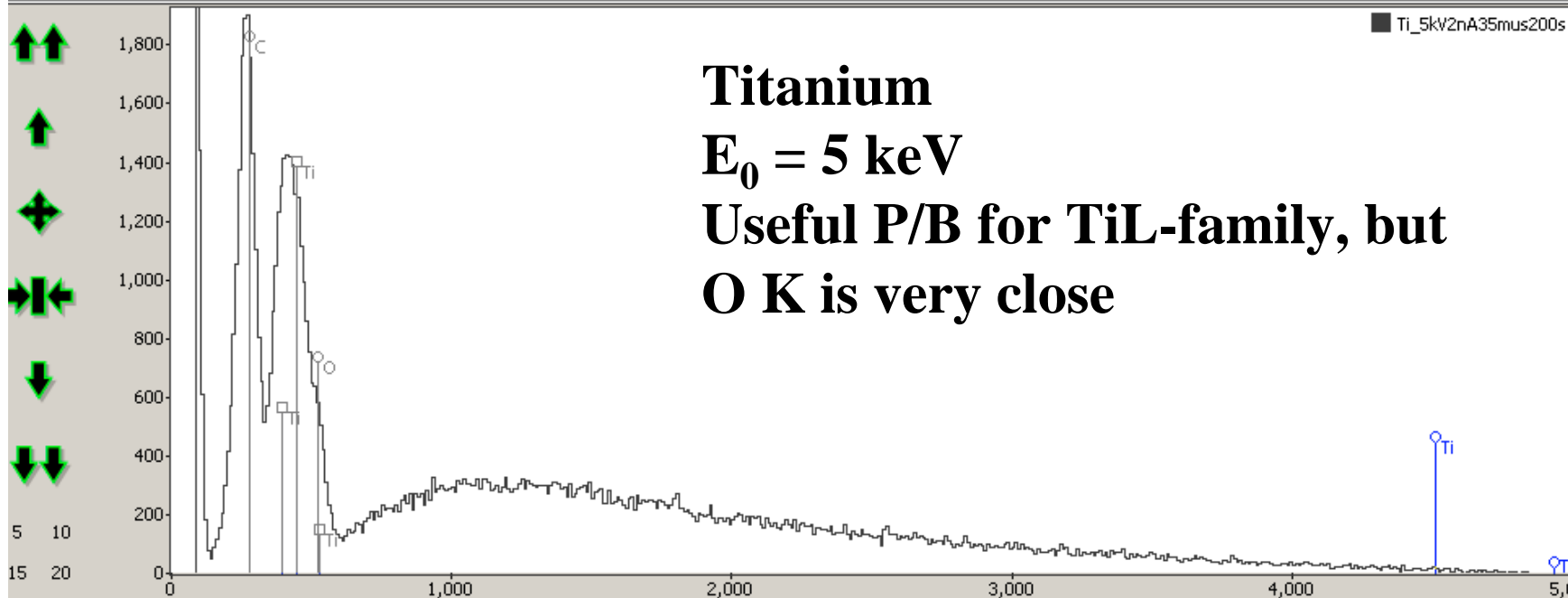
Sensitivity to False Peaks: Unstable Solution Changes with Time



Photon Energy (keV)

Peak ID for Low Voltage Microanalysis ($E_0 \leq 5$ keV)

- $E_0 = 5$ keV is the lowest energy for which the entire Periodic Table (except H, He, Li) is accessible by EDS, although some elements are just barely detectable, e.g., Cs, Ba
- Operating with LVSEM conditions ($E_0 \leq 5$ keV) eliminates K- and L- shell information critical for robust peak ID obtained from peaks with photon energies > 5 keV.
- Unfamiliar L- and M- shells must be used instead.
- The fluorescence yield of these low photon energy L- and M- shell peaks is often very low, resulting in low P/B, even from pure elements
- The intensity relationships among family members may behave in unexpected ways.
- As E_0 is reduced below 5 keV, significant portions of the Periodic Table become inaccessible by EDS, even for pure elements



Titanium
 $E_0 = 5 \text{ keV}$
 Useful P/B for TiL-family, but
 O K is very close

Spectrum Report Command

Default Detector

8600 Probe
 EDAX_35mus

Spectrum List

Ti_5kV2nA35mus200s

None All Clear

Spectrum Properties

Name	Value
Acquisition time	8/29/06 11:42 AM
Aluminum layer thickness	0 nm
Aluminum window thickness	30 nm
Azimuthal angle	0 °
Beam energy	5 keV
Dead layer	0.1 μm
Detector	EDAX_35mus - FWHM[Mn Kα]=134.0 eV - initial
Detector area	30 mm²
Detector orientation	[-0.814,-0.000,0.582]
Detector position	[80.435,0.000,-57.493]
Detector thickness	5 mm
Detector type	Si(Li)
Detector window	Moxtek AP 3.3 (manufacturer's table)

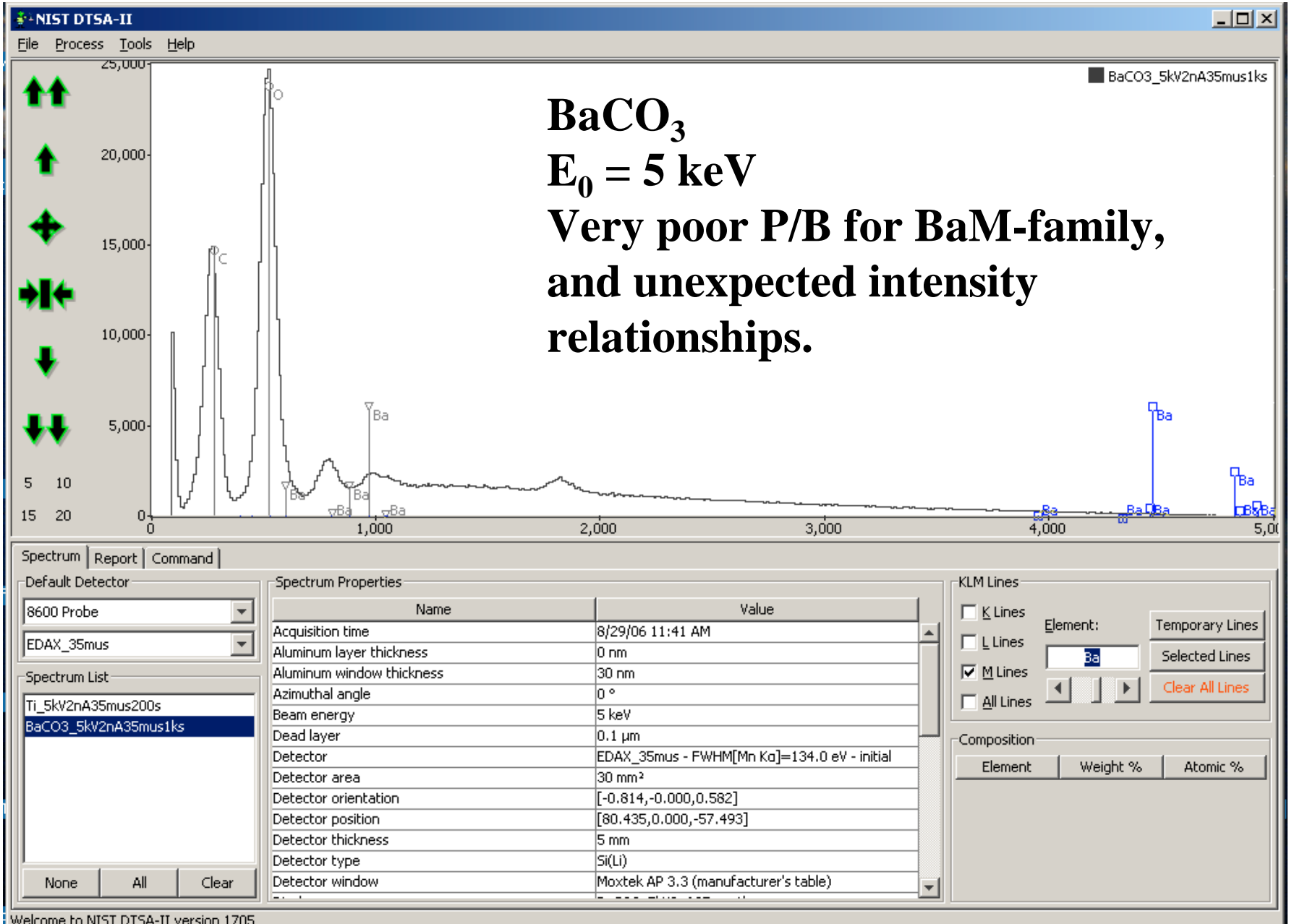
KLM Lines

K Lines
 L Lines
 M Lines
 All Lines

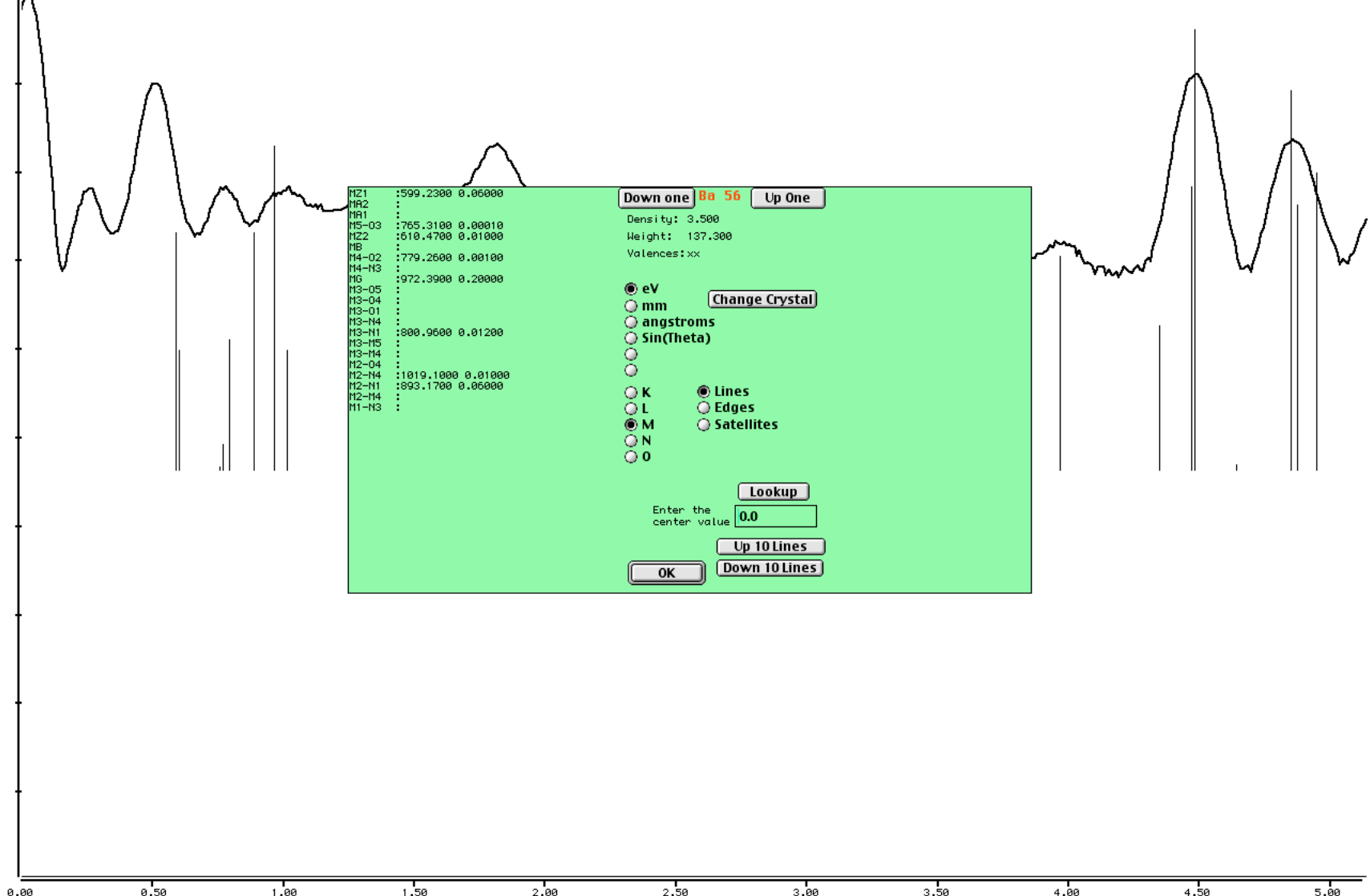
Element: Ti
 Temporary Lines
 Selected Lines
 Clear All Lines

Composition

Element	Weight %	Atomic %



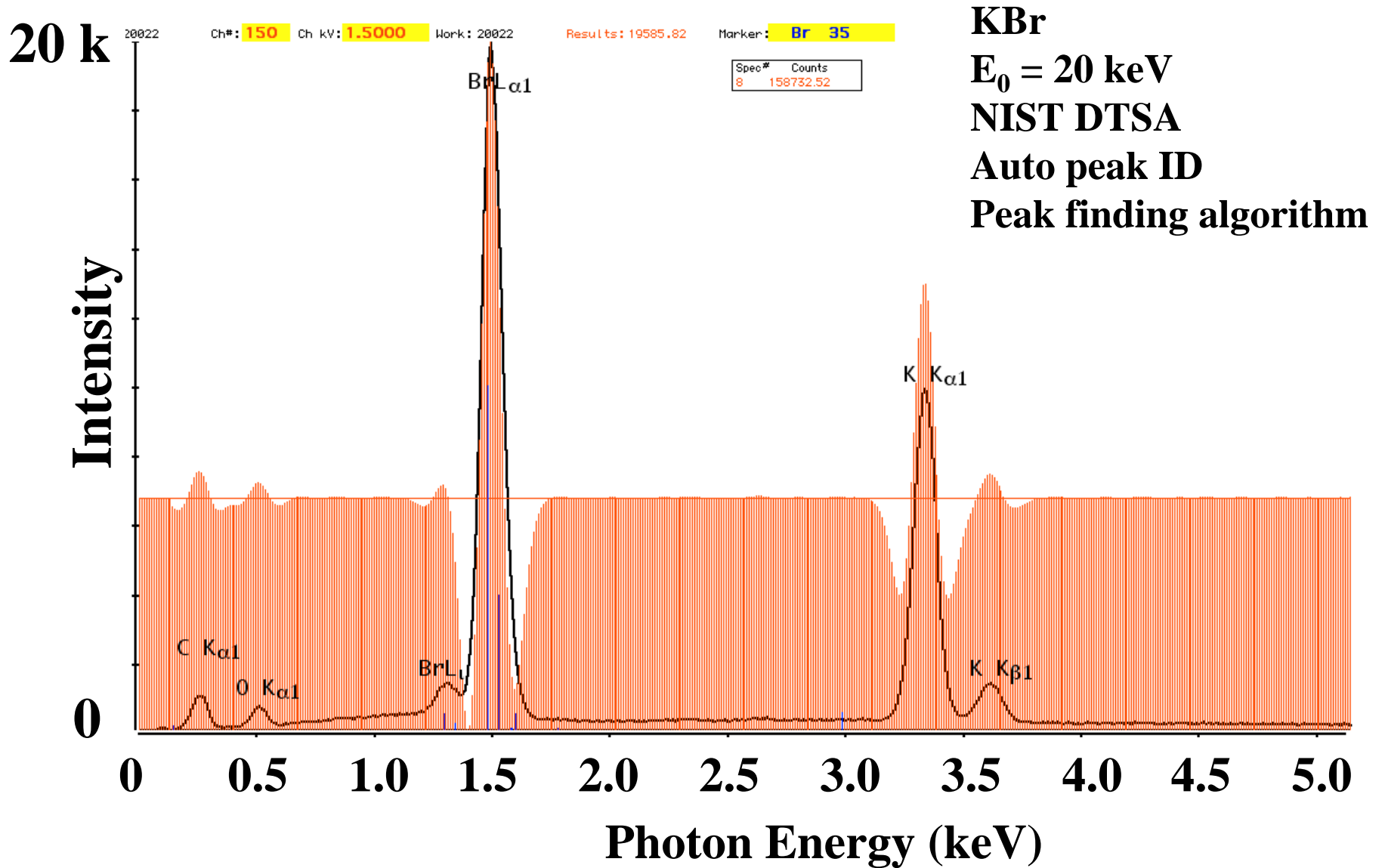
4.32 Ch#: 111 Ch KV: 1.1100 Work: 1998 Results: 0 Marker: Ba 56



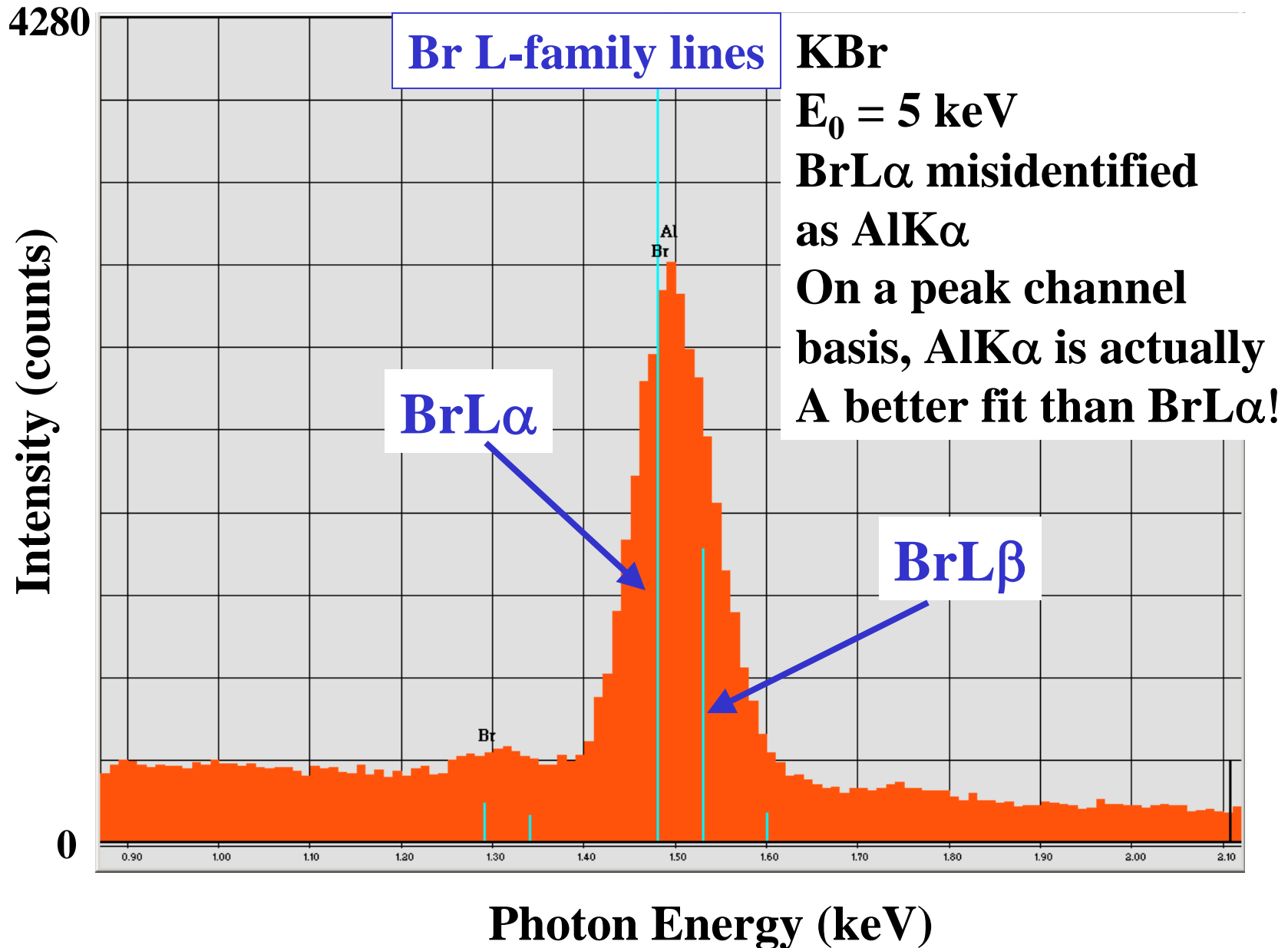
Why does automatic Peak ID fail?

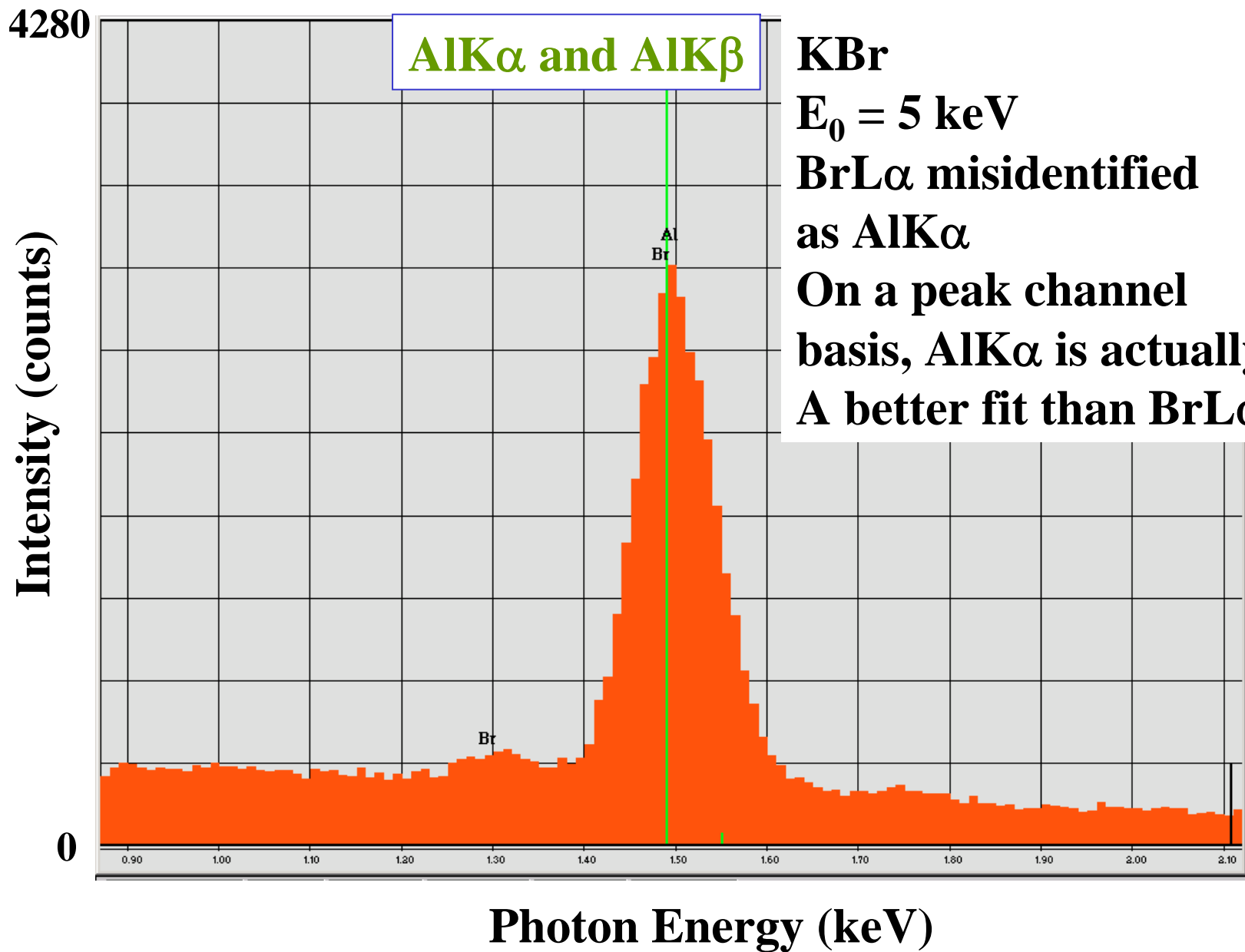
- Apparent reliance on the “single channel” solution

What is going on here? Basic Peak ID finds the peak channel only and then proceeds to a look-up table!



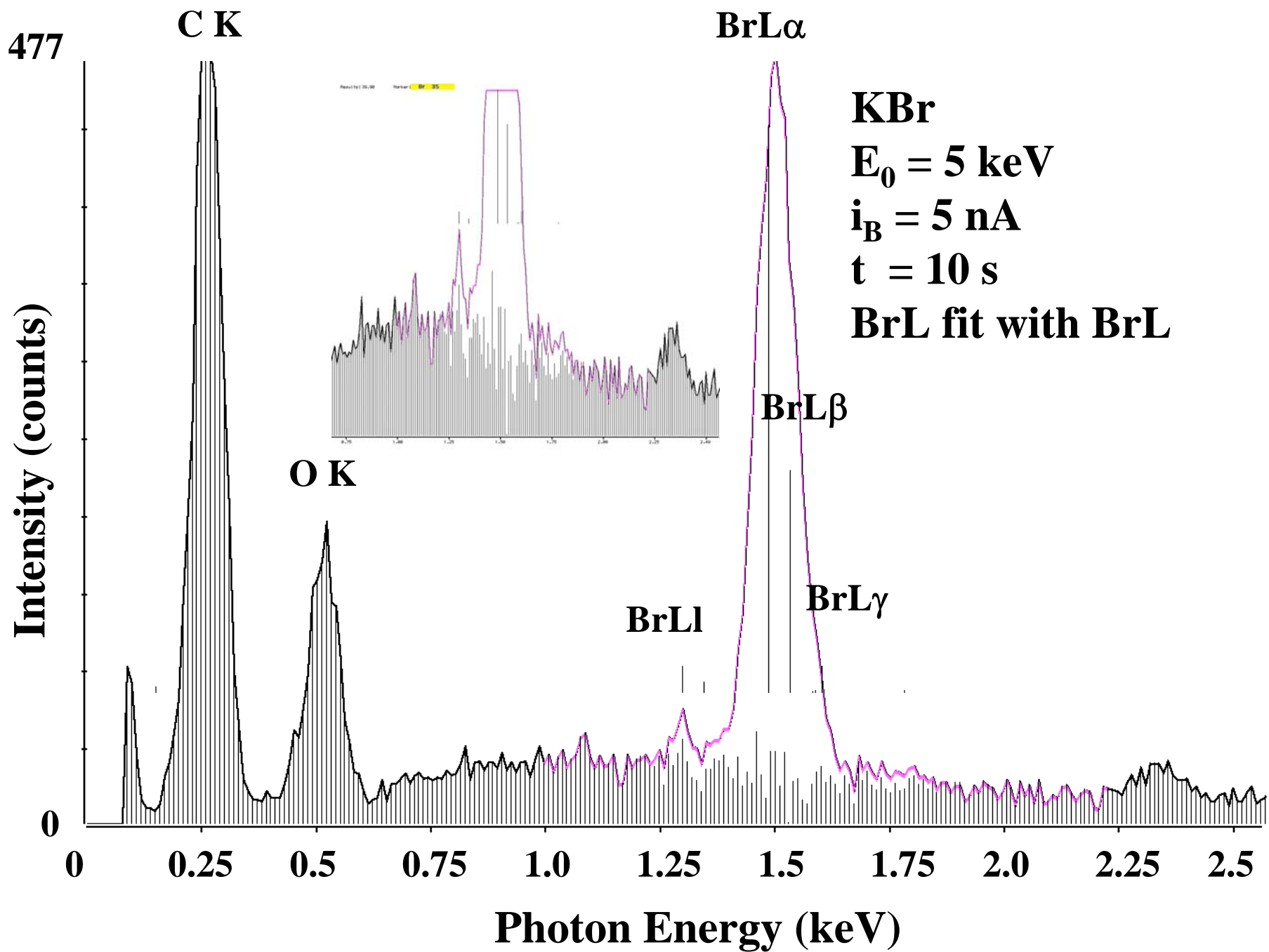
Basic single channel Peak ID is vulnerable to convolution of family members

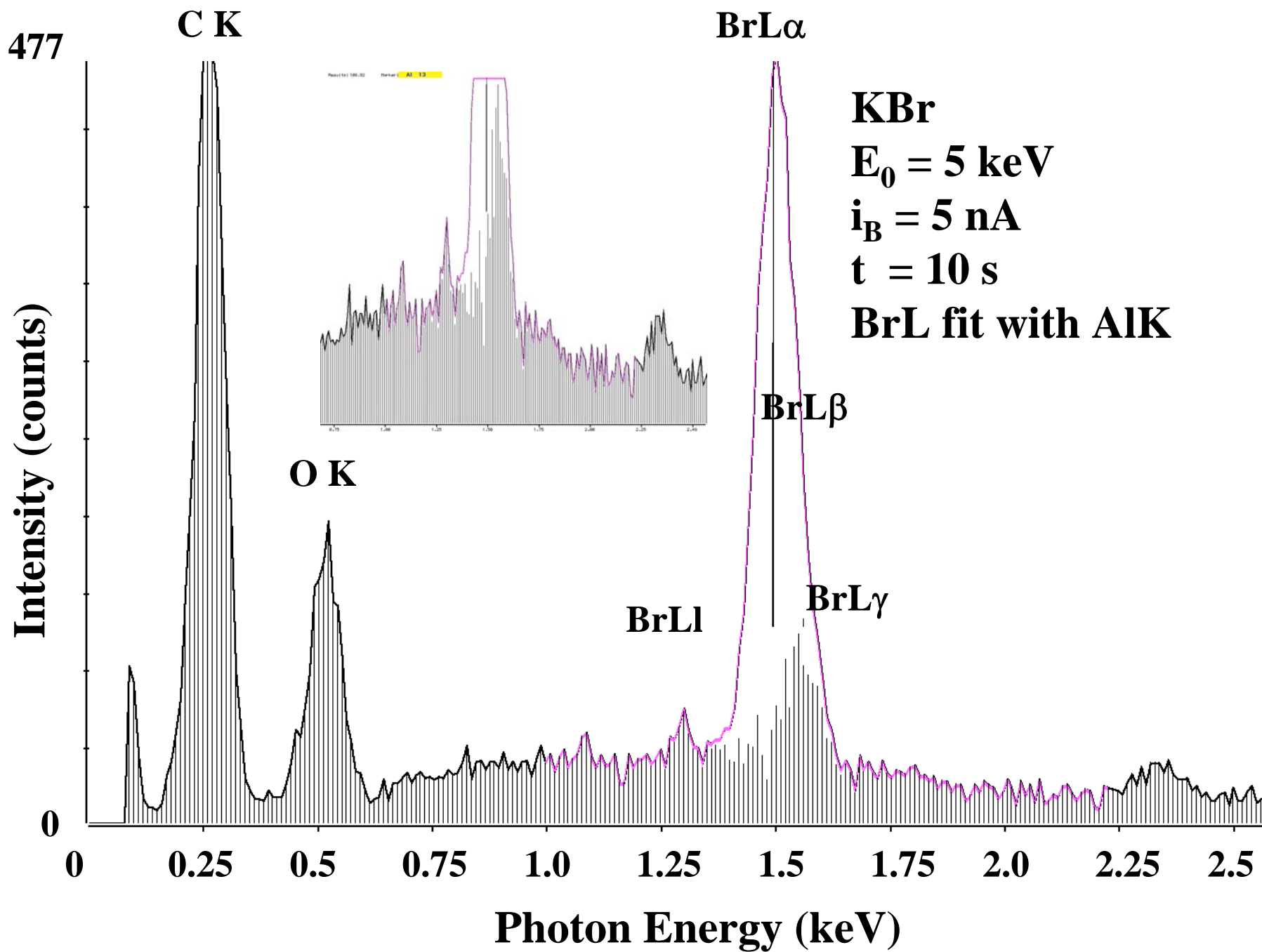


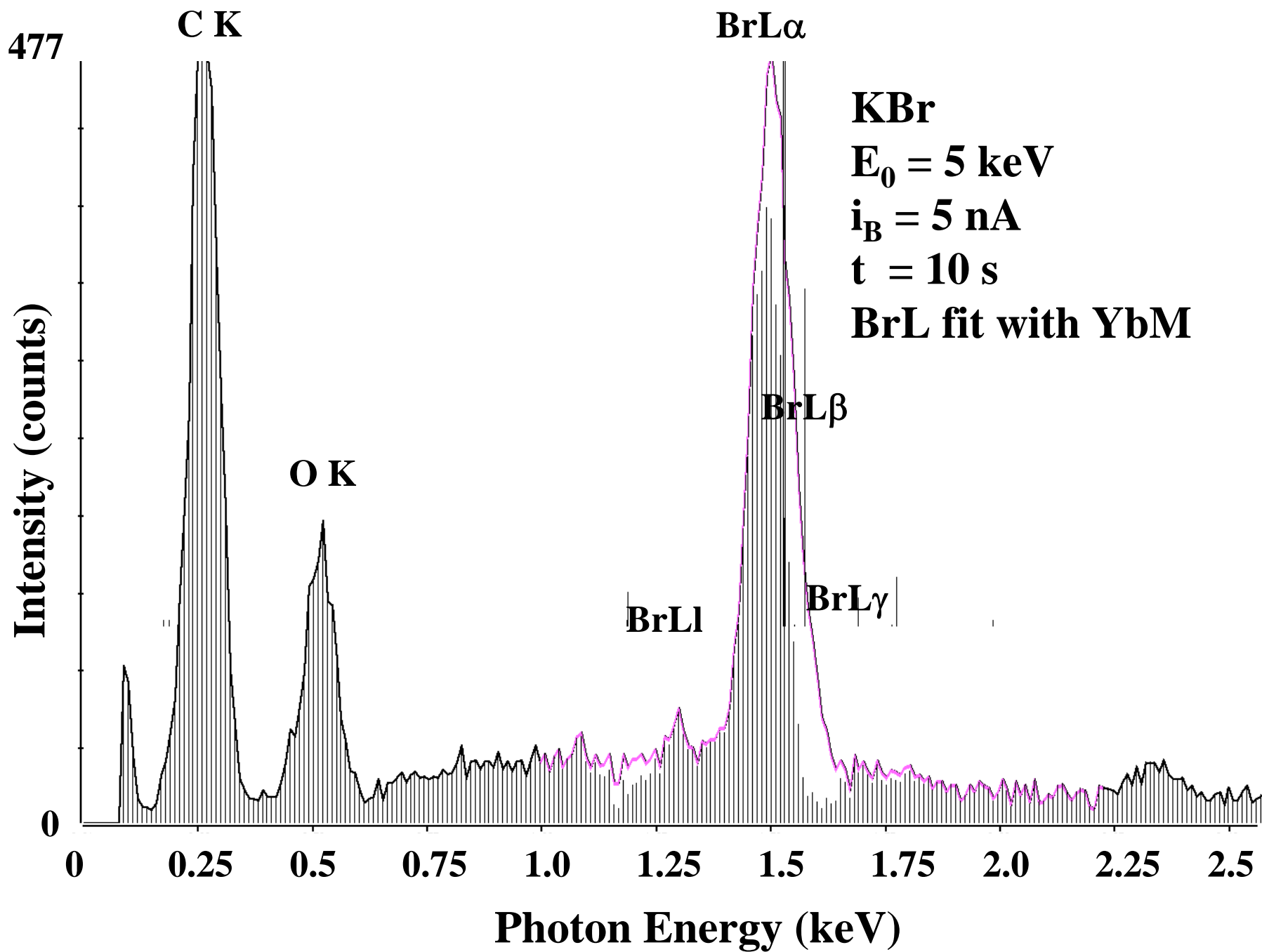


A more robust approach: multiple linear least squares (MLLS) fitting

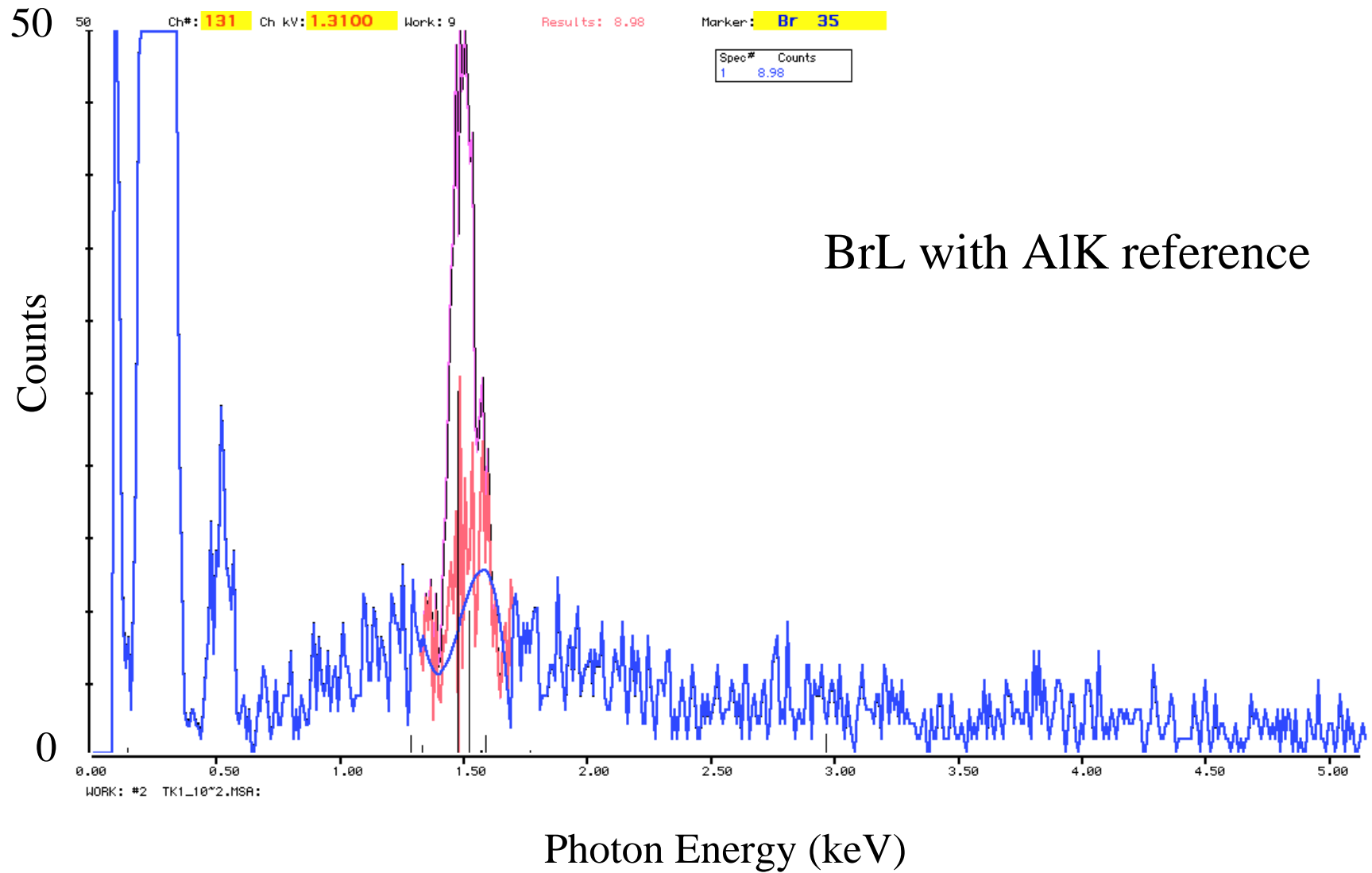
- Locate candidate peak
- Determine possible elemental families, e.g., AlK, BrL, YbM for $E = \sim 1.5 \text{ keV}$
- Fit the peak reference over the full range of channels necessary to span family
- Test and compare residuals after fitting



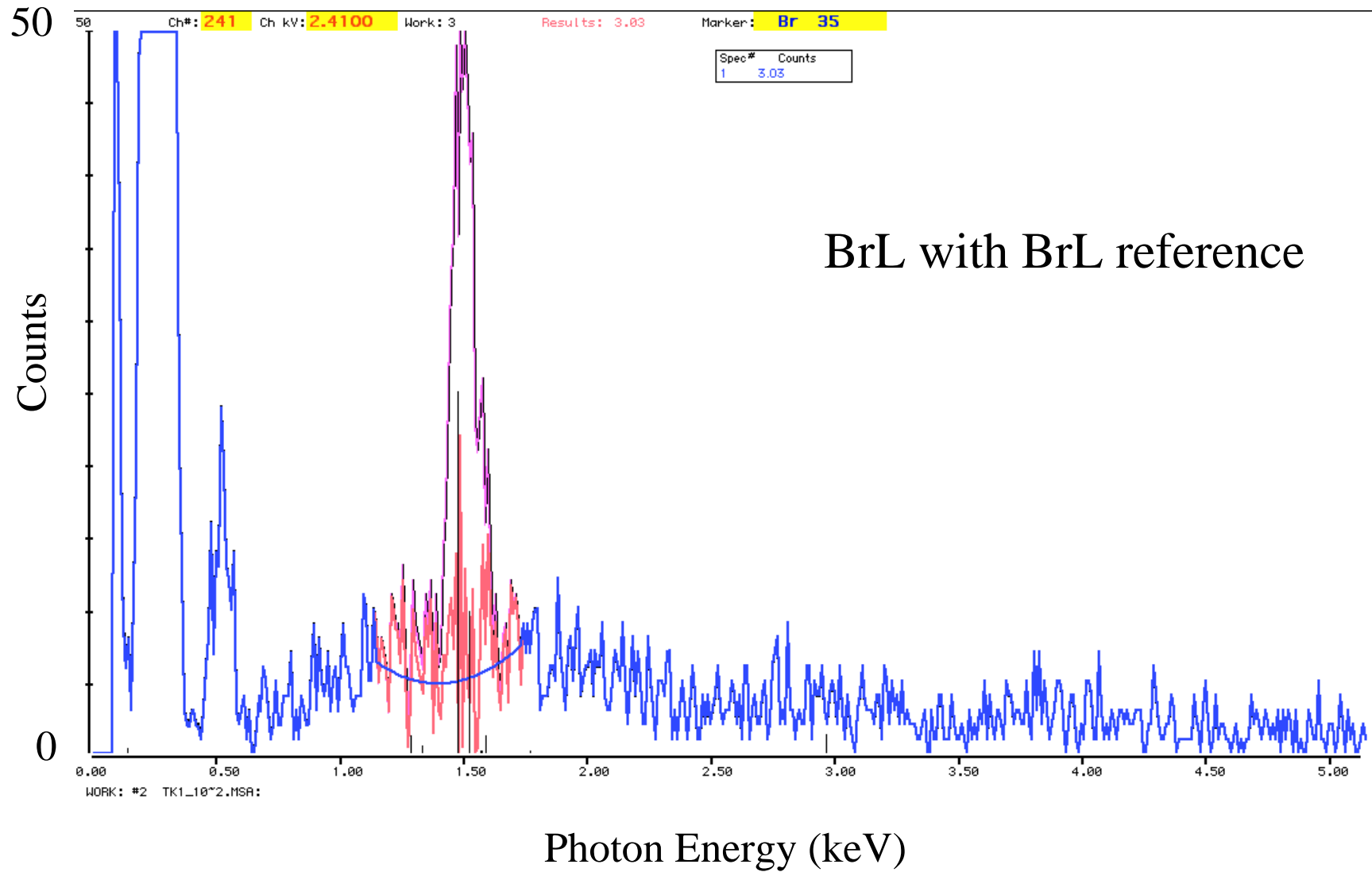




1/10 of the dose of the previous example



1/10 of the dose of the previous example



Summary of blunders observed with Automatic Peak Identification under conventional beam energy conditions ($10 \leq E_0 \leq 30$ keV)

- It is estimated that if the entire Periodic Table (except H, He, and Li) is in play, about 3% to 5% of automatic peak IDs of major elements result in blunders (e.g., SiK instead of TaM; AlK instead of BrL).
- These blunders are not random mistakes. The same element/peak in different systems will be consistently misidentified, e.g., AlK for BrL in various Br-compounds.
- These blunders occur despite high counting statistics.
- In some EDS systems, identifying a high energy K or L peak does not eliminate the blunder on the corresponding low energy L or M peak; e.g., ZnK-ZnL (NaK)
- Poor EDS calibration makes the problem much worse!!
- The problem is worse for minor and trace constituents
- The problem is worse for low voltage ($E_0 \leq 5$ keV) microanalysis